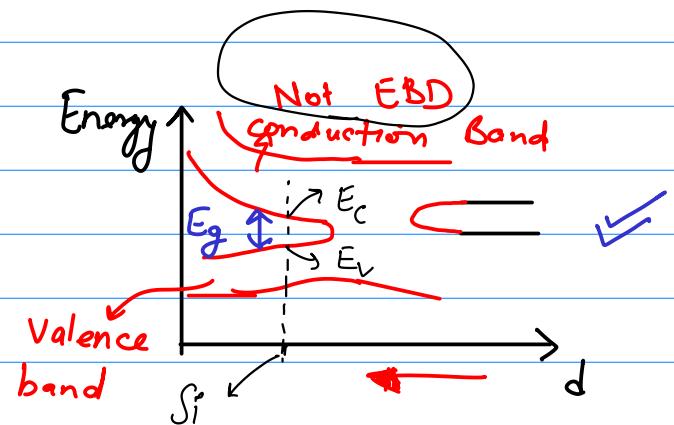
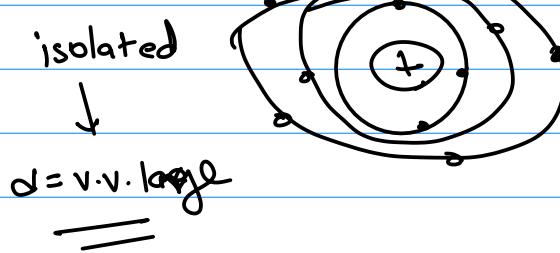


Microelectronics Jacob Millman, Arvin Grabel  
 (or) Microelectronic Millman , Halkias  
 Sedra & Smith

→ Energy Band Diagrams - (EBD)

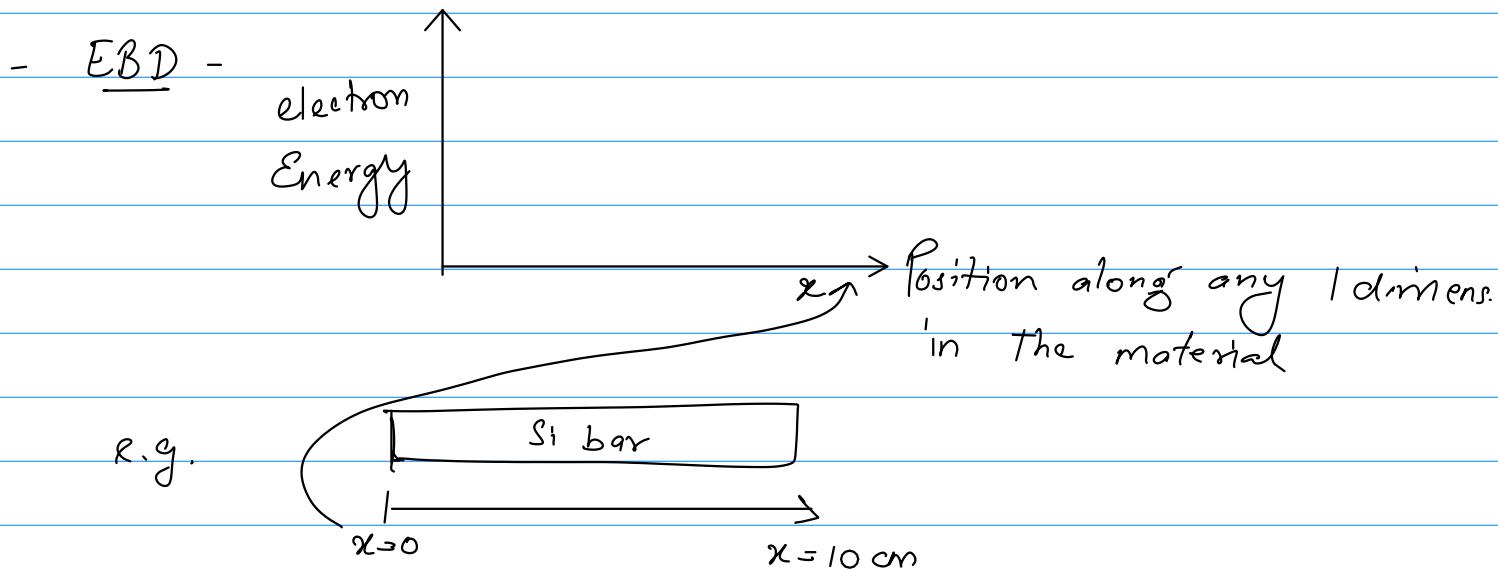


$d$  = inter atomic distance

$Eg$  = Forbidden energy gap.  
 (band gap)

What if  $d \downarrow$

- ① as  $d \downarrow$ ,  $Eg \uparrow$ . for constant  $d$  (1 material),  $Eg = \text{constant}$
- ② For 1 material,  $d$  is fixed (constant) under certain external condition, e.g.,  $T$  (temperature)

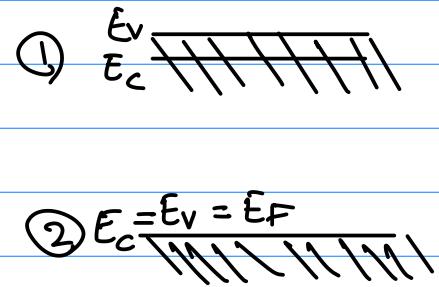
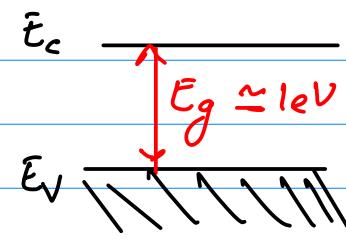
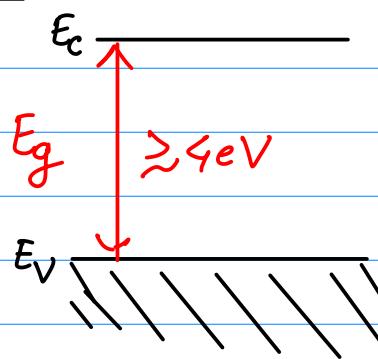


3 types  
of materials

Insulator

Semi  
Conductor

Conductor



- What is eV?

$$1\text{e} = \begin{matrix} \text{mag. of} \\ \text{\^{} charge of } 1\text{e} \end{matrix} \begin{matrix} (\text{energy}) \\ \text{C} \end{matrix}$$
$$= 1.6 \times 10^{-19} \text{ C}$$

$$1\text{eV} = 1.6 \times 10^{-19} \text{ C} \times 1\text{V} = 1.6 \times 10^{-19} \text{ J}$$

$$1\text{eV} = 1.6 \times 10^{-19} \text{ J}$$

$$\text{energy Joules, } 1\text{J} = 1\text{C} \times 1\text{V}$$
$$W = Q, V$$

- What is conduction band →

Energy levels available to be occupied by  $e^-$ s which are free of bonds (free to move anywhere in the material).

Hence  $e^-$ s are conducting  $e^-$ s.

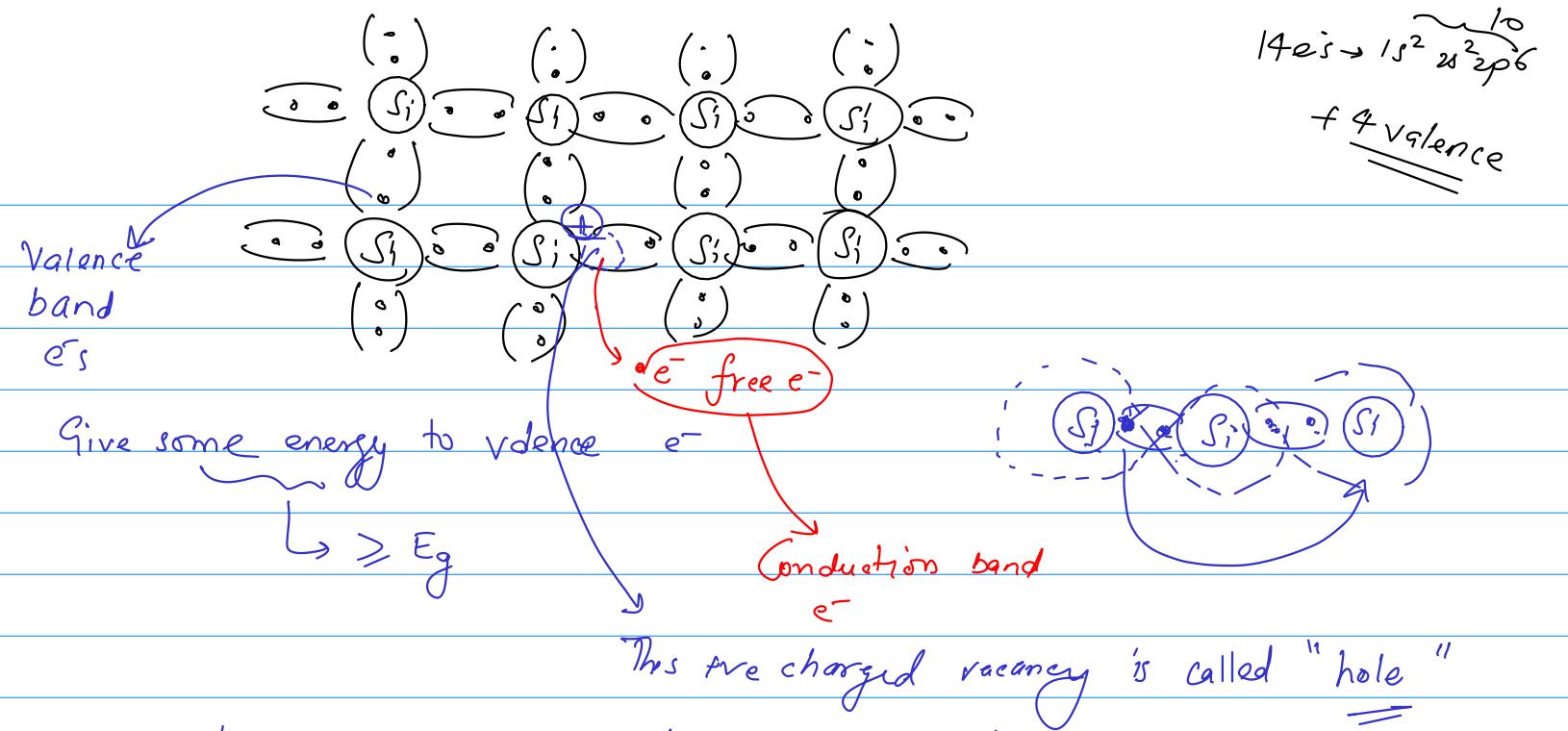
- What is valence band -

Energy levels occupied by  $e^-$ s that are bonded (not free to move except around their nucleus)

→ Semiconductors - Silicon (Si,  $Z = 14$ )  
(atomic no.) , Ge , GaAs

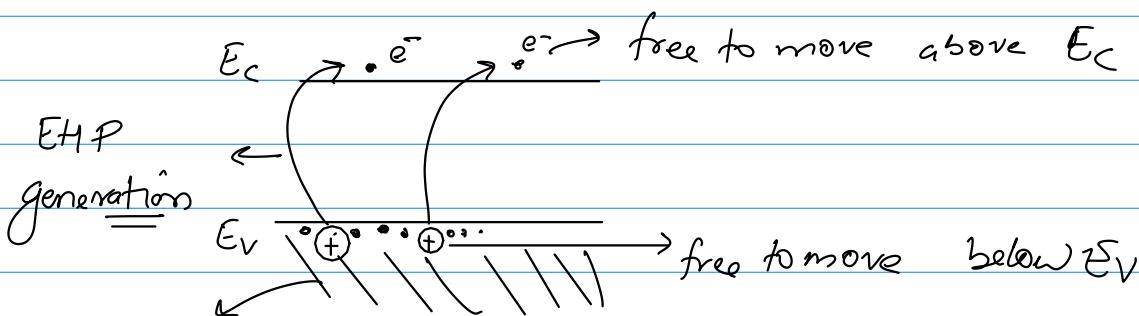
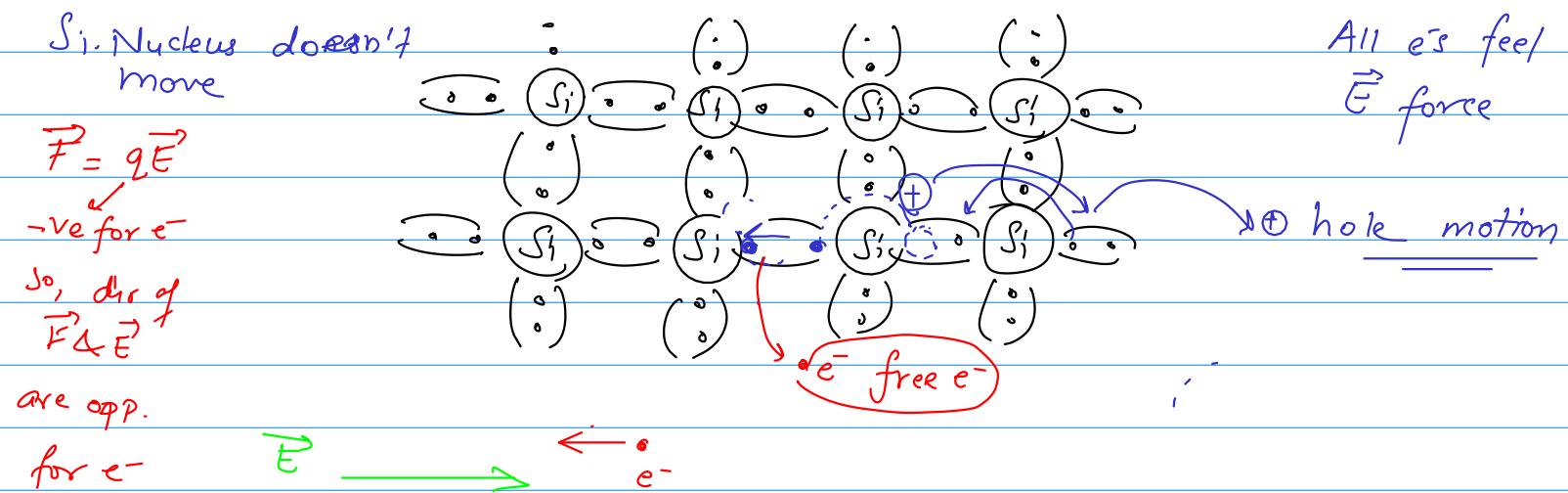
$$14e^- \rightarrow 1s^2 2s^2 2p^6$$

+ 4 valence



This free charged vacancy is called "hole"

- \* holes are vacancies in valence band
  - They are free to move in the valence band.
  - \* free e⁻'s are in cond. band & they are free to move
- So, there are 2 types of charge carriers in a semi-conductor.

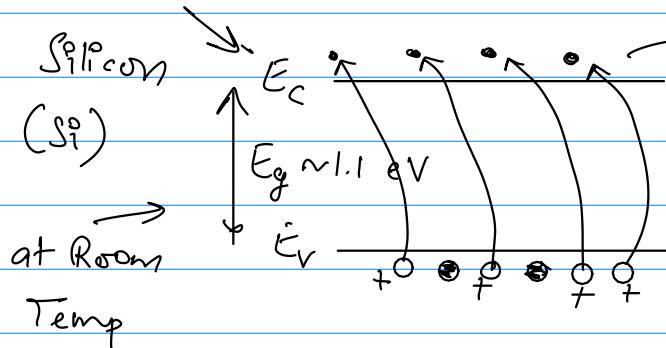


Shading means lots & lots of e⁻'s (but not free to move)

Aug 11)

## → Types of s.c. -

1. Intrinsic semi cond. - Pure, no impurities (or doping)



Thermally generated Electron-hole pairs (EHPs)

e.g. in Si,

Let  $n = \text{no. of } e^- \text{ cm}^{-3}$   
 $p = \dots \text{ holes cm}^{-3}$

$$\text{at room temp, } n = p = n_i \approx 1.5 \times 10^{10} \text{ cm}^{-3}$$

↓  
intrinsic carrier conc.

$$\text{Atomic Density of Si} \approx 5 \times 10^{22} \text{ cm}^{-3}$$

So,  $n_i \ll \text{atomic density}$

\* Intrinsic semi cond. have very low conductivity.

$$\left. \begin{array}{l} * n_i \uparrow \text{ if } T \uparrow \\ * n_i \downarrow \text{ if } E_g \uparrow \end{array} \right\} \quad \boxed{n_i = A \exp\left(-\frac{E_g}{2kT}\right)}$$

where  $A \propto T^{3/2}$

$$n_i = A C^{\left(-\frac{E_g}{kT}\right)}$$

$k = \text{Boltzmann's constant}$

$$kT = \frac{T}{11600} \text{ eV}$$

where  $T$  is in Kelvin

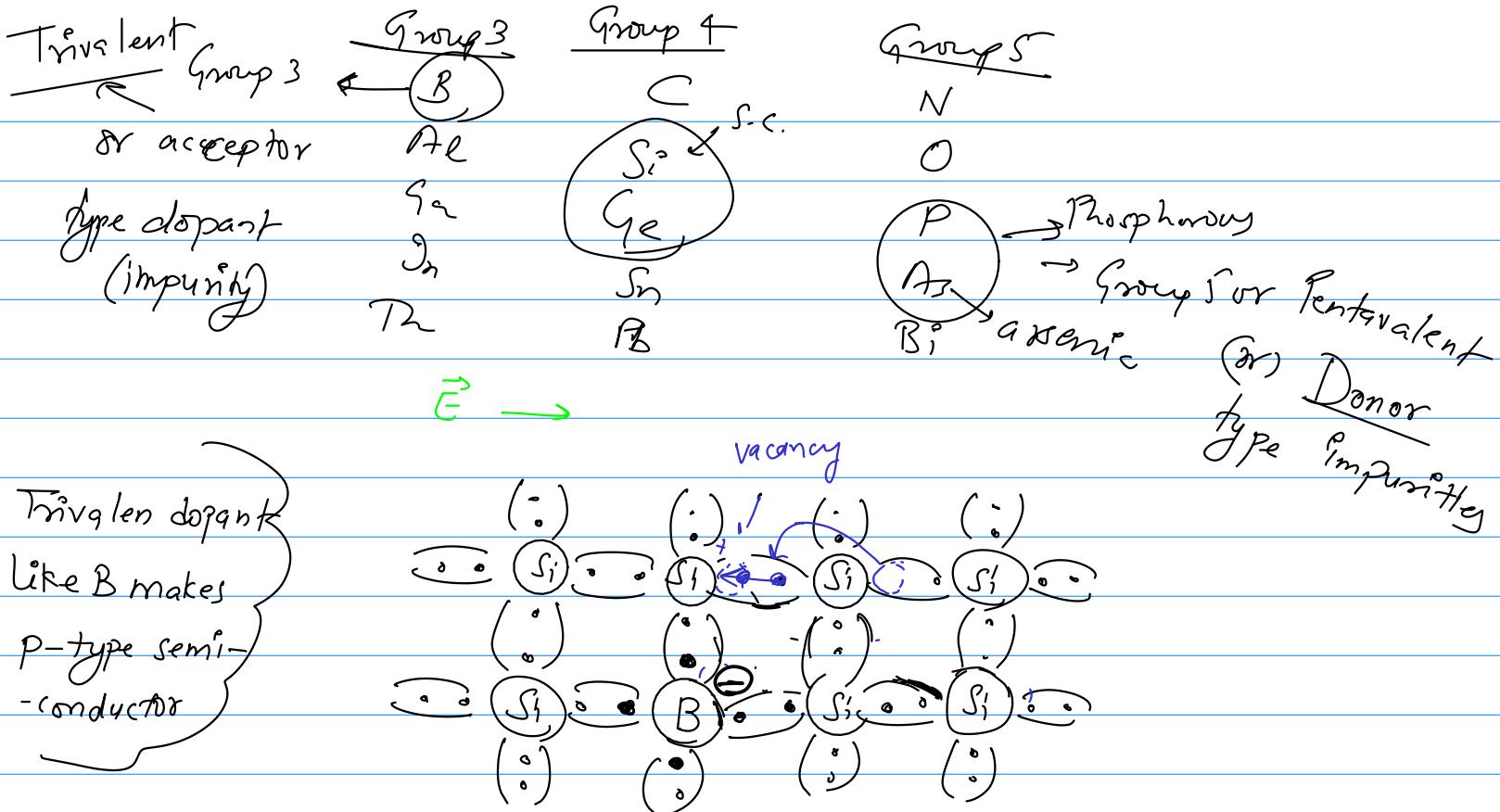
at room temp ( $T = 300 \text{ K}$ )

$$kT \approx 26 \text{ m eV}$$

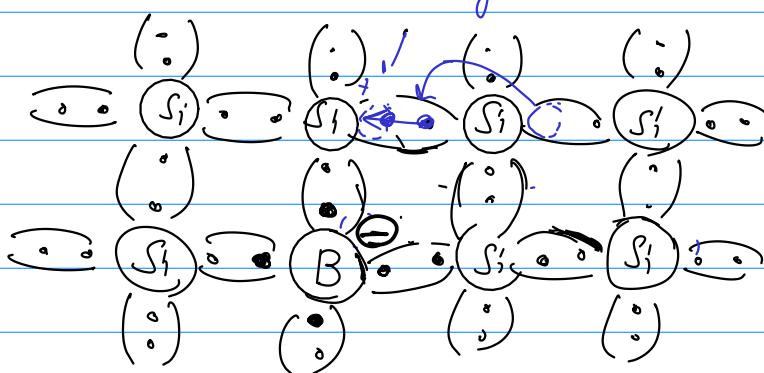
unit of energy

$$1 \text{ eV} = \frac{1 \times 1.6 \times 10^{-19} \text{ C} \times \text{V}}{\text{J}} = 1.6 \times 10^{-19} \text{ Joules}$$

→ Extrinsic Semiconductors - impure (or doped)



Trivalent dopant  
like B makes  
p-type semi-conductor



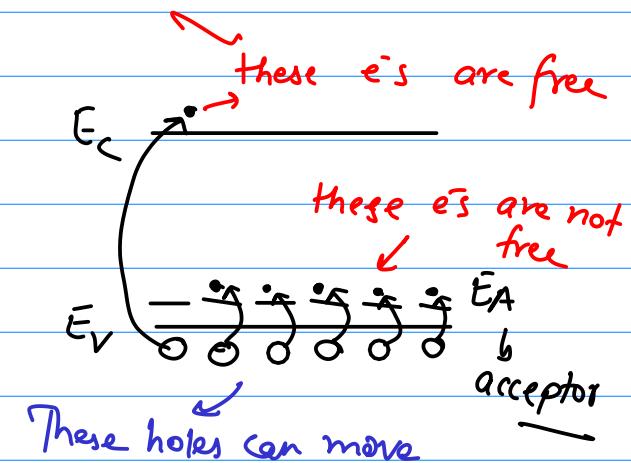
as a result, 1 B atom causes creation of 1 hole  
(without any free  $e^-$  generation)

(any dopant ion)

- \*  $B^{-1}$  charge is immobile
- \*  $Si^+$  → hole can move.

$E_A$  is v. close  $E_V$

$$E_A - E_V \sim 0.05\text{eV}$$



$Si$  has  $5 \times 10^{22} \text{ cm}^{-3}$  atoms at room temp

If there 1 B atom per  $10^8 Si$  atoms

$$\text{then B concentration} = N_A = 5 \times 10^{14} \text{ cm}^{-3}$$

At room temp- every  $\downarrow$  B atom gives 1 hole & 0  $e^-$ .

$$\text{So hole conc. } p = N_A + (\text{thermally Generated})$$

as we saw  $n_i = \underline{1.5 \times 10^{10} \text{ cm}^{-3}}$   $\rightarrow$  hole conc. before doping

$$N_A = 5 \times 10^{14} \text{ cm}^{-3}$$

$\hookrightarrow$  doping.  $p = N_A + \underline{\text{thermal gen.}}$

$$N_A \gg n_i, p \approx N_A = 5 \times 10^{14} \text{ cm}^{-3}$$

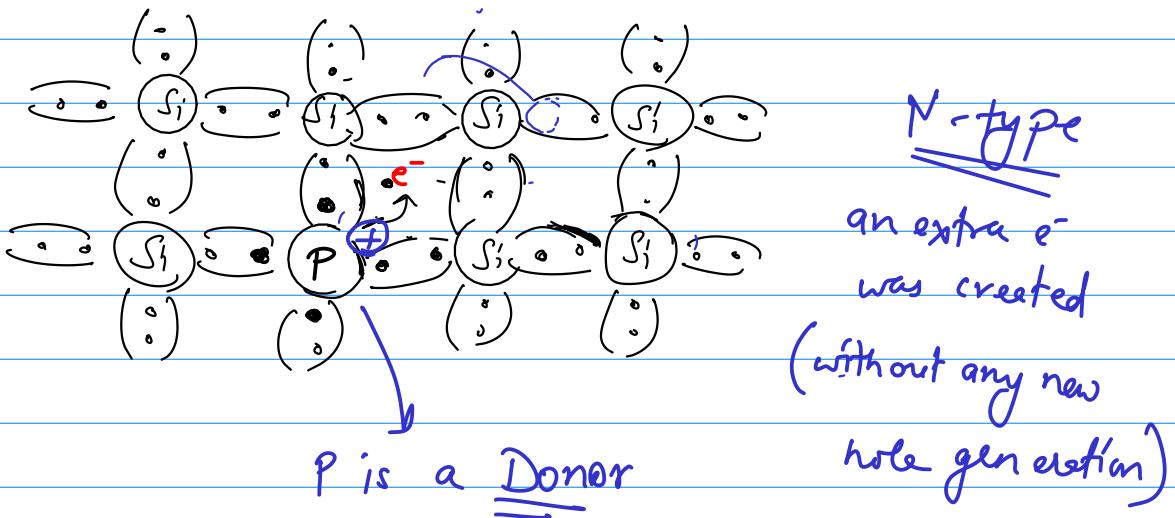
$\rightarrow$  In p-type s.c.  $p > n$  &  $p \gg n_i$   
So, we say that holes are the 'majority carriers'

$\rightarrow$  In any extrinsic s.c., Maj. carrier conc.  $\cong$  Doping conc.  
(at room temp.)

$\rightarrow$  N-type s.c.  $\rightarrow$  Dopants  $\rightarrow$  P or As

Pentavalent

+ve charge  
on  $P^+$   
is 'immobile'



$$\bar{E}_c - \bar{E}_D \approx 0.05 \text{ eV}$$



At room temp, every Donor atom releases  $1 e^-$  into conduction band.

Let  $\underline{\text{Ph. conc.}} = N_D = 5 \times 10^{14} \text{ cm}^{-3}$

$\downarrow$   
Donor

then  $n = N_D + (\text{thermally gen.})$

$$n_i \sim 1.5 \times 10^{10} \text{ cm}^{-3} \quad N_D \gg n_i$$

so,  $n \approx N_D \simeq 5 \times 10^{14} \text{ cm}^{-3}$

→ Donor impurity makes n-type s.c.

→ In n-type s.c., electrons are majority carriers  
 $(\because n \gg p \quad \& \quad n \gg n_i)$

→ In any extrinsic s.c., majority conc.  $\approx$  Doping conc.  
 $(\text{at room temp.})$

→ Law of Mass action - Under thermal equilibrium,

$$n \cdot p = n_i^2 \rightarrow \text{valid for both intrinsic \& extrinsic s.c.}$$

→ Minority conc. - Law of mass action is used to find this

let's take p-type s.c.  $p = N_A$

then e<sup>-</sup> conc. n under equilibrium can be found from  $np = n_i^2$

$$n = \frac{n_i^2}{p} \approx \frac{n_i^2}{N_A}$$

Similarly, for n type s.c.,

Majority  $\rightarrow$

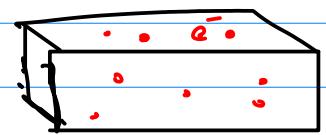
$$n \approx N_D$$

minority

$$p = \frac{n_i^2}{n} \approx \frac{n_i^2}{N_D}$$

$\rightarrow$  Charge conservation in s.c. - Total charge in material is always conserved.

So, sum of all charges = 0



Charge Neutrality.

-ve charges - free e<sup>-</sup>s  $\rightarrow n$   
Acceptor ions  $\rightarrow N_A^- \approx N_A$  (at room temp)

+ve charge - holes  $\rightarrow p$   
Donor ions  $\rightarrow N_D^+ \approx N_D$  (at room temp)

let the s.c. be doped with both donors & acceptors  
(General Case)

Charge Neutrality  $\rightarrow$  (total +ve charges) + (total -ve charges) = 0

$$p + N_D^+ - (n + N_A^-) = 0$$

where  $q = +1.6 \times 10^{-19} C$

$$p + N_D^+ = n + N_A^-$$

at room temp

$$\boxed{p + N_D = n + N_A} \quad **$$

if  $N_A \gg N_D$  &  $N_A \gg n_i$

$$p + N_D - n - N_A = 0$$

Also, even  $n \approx n_i$ ,  
(which it isn't),

$$p - N_D - N_A = 0, \quad p - N_A = 0 \Rightarrow p = N_A$$

If  $N_A \gg n$ ; but  $N_A > N_D$  (not too large)

$$p + N_D - N_A = 0 \Rightarrow p - (N_A - N_D) = 0$$

$$\Rightarrow p = N_A - N_D \quad \begin{matrix} \text{maj. conc} \\ \text{in p-type} \end{matrix}$$

Similarly if  $N_D \gg n$ ,  $N_D > N_A$

then  $p$  is neglected, &

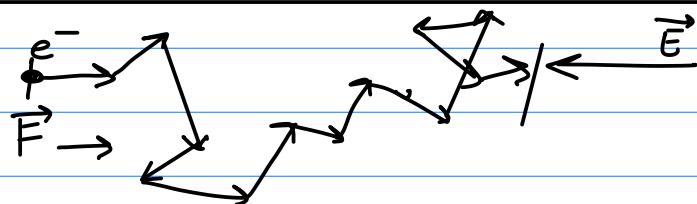
$$n = N_D - N_A$$

$\downarrow$   
maj conc. in n-type s.c.

\* Now minority conc. can be found from Law of mass action.

### → Conduction in s.c. - 2 processes

#### 1. Drift



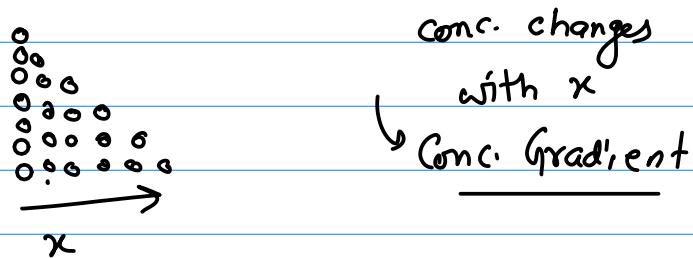
Collisions  $\Rightarrow$  Scattering

e's don't have Newtonian vel.  
they have  $v_d$  (Drift velocity)

$$v_d \propto E \Rightarrow v_d = \mu E$$

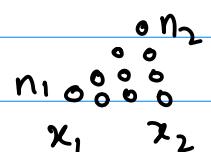
$\mu$  = Mobility

#### 2. Diffusion



particles move from high conc. to low conc.

for e's, - if  $\frac{dn}{dx} = +ve$



$$n_2 > n_1, \quad x_2 > x_1 \quad \frac{n_2 - n_1}{x_2 - x_1} \approx \frac{dn}{dx}$$

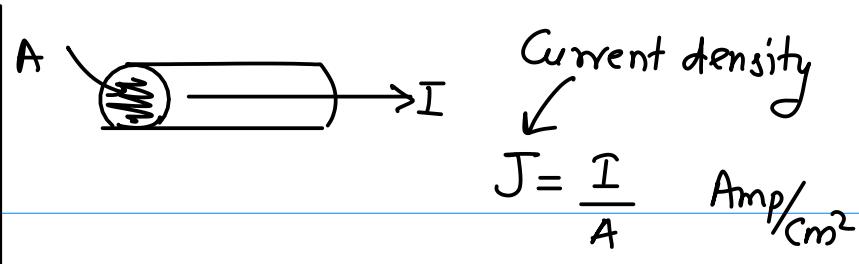
+ve

e's will move in  $-x$  direction  
I will be in  $+x$  direction

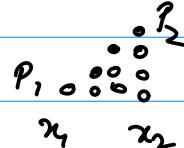
Diffusion-  
Current density  
due to  $\text{e}^-$ s

$$q = +1.6 \times 10^{-19} \text{ C}$$

$$J_{n\text{-diff}} \propto q D_n \frac{dn}{dx}$$



for holes - if  $\frac{dp}{dx} = +ve$



$$P_2 > P_1 \quad \frac{P_2 - P_1}{x_2 - x_1} = \frac{dp}{dx} = +ve$$

holes will move in -ve x direction  
& I will be in -ve x dir.

$D_n, D_p$   
Diffusion  
constant

So,

$$J_{p\text{-diff}} = -q D_p \frac{dp}{dx}$$

$$q = +1.6 \times 10^{-19} \text{ C}$$

Drift Current - Caused by electric field (force, pot.-diff)

$$J_{\text{drift}} \propto \underbrace{\epsilon}_{\text{electric field}}$$

$$J_{\text{drift}} = \sigma \epsilon$$

Ohm's law

conductivity

$$\underline{\text{Ohm's Law}} - V = IR \quad I = \frac{1}{R} V$$

$$\text{Amp} = \frac{1}{\text{Ohm}} \times \text{Volts}$$

Resistance  
 $R = \rho \frac{l}{a}$  length  
resistivity  $\rho$  section area

$$\rho = \Omega \text{hm} \cdot \text{cm}$$

$$\frac{1}{\rho} = \sigma = \frac{1}{\Omega \text{hm} \cdot \text{cm}}$$

Current density

$$\frac{\text{Amp}}{\text{cm}^2}$$

$$= \left( \frac{1}{\Omega \text{hm} \cdot \text{cm}} \right) \left( \frac{\text{Volt}}{\text{cm}} \right)$$

$$J = \sigma \cdot \epsilon$$

electric field

$$\rightarrow \text{Conductivity} - \sigma = \frac{1}{\rho} \rightarrow \text{resistivity} (\Omega \text{cm})$$

$$\sigma \rightarrow \frac{1}{\Omega \text{cm}}$$

$$\sigma_n \propto n ; \quad \sigma_n \propto \mu_n \quad \therefore \quad \sigma_n \propto \frac{1}{\text{scattering}} \quad \mu \propto \frac{1}{\text{scattering}}$$

$$\boxed{\sigma_n = q n \mu_n}$$

Similarly  $\boxed{\sigma_p = q p \mu_p}$

Total conductivity for any s.c. -

$$\boxed{\sigma = \sigma_n + \sigma_p = q n \mu_n + q p \mu_p}$$

Intrinsic Conductivity (for intrinsic s.c.)  $\rightarrow$

$$n = p = n_i$$

so,

$$\boxed{\sigma_i = q n_i (\mu_n + \mu_p)}$$

if for n-type s.c.,  $n \gg p$  then  $n \mu_n \gg p \mu_p$   
 $\therefore \sigma \approx q n \mu_n$  (total conductivity)

since  $n \approx N_D$  then

$$\boxed{\sigma \approx q N_D \mu_n}$$

if for p-type s.c.,  $p \gg n$  then  $p \mu_n \gg n \mu_p$

&  
since  $q \approx N_A$

$$\boxed{\sigma \approx q p \mu_p}$$

$$\therefore \boxed{\sigma \approx q N_A \mu_p}$$

Conduction equations - Total current density,  $J = J_n + J_p$

where  $J_n = J_{n\text{drift}} + J_{n\text{-diff}}$

$\leftarrow J_p = J_{p\text{drift}} + J_{p\text{diff}}$ .

So,

$$J_n = q n v_{dn} + q D_n \frac{dn}{dx}$$

&  $J = J_n + J_p$

$$J_p = q p v_{dp} - q D_p \frac{dp}{dx}$$

$$v_{dn} = \mu_n E$$

$$v_{dp} = \mu_p E$$

→ Einstein's Relation -

$$\frac{D}{\mu} = \frac{kT}{q}$$

$$kT = \frac{T}{11,600} \rightarrow \text{in Kelvin}$$

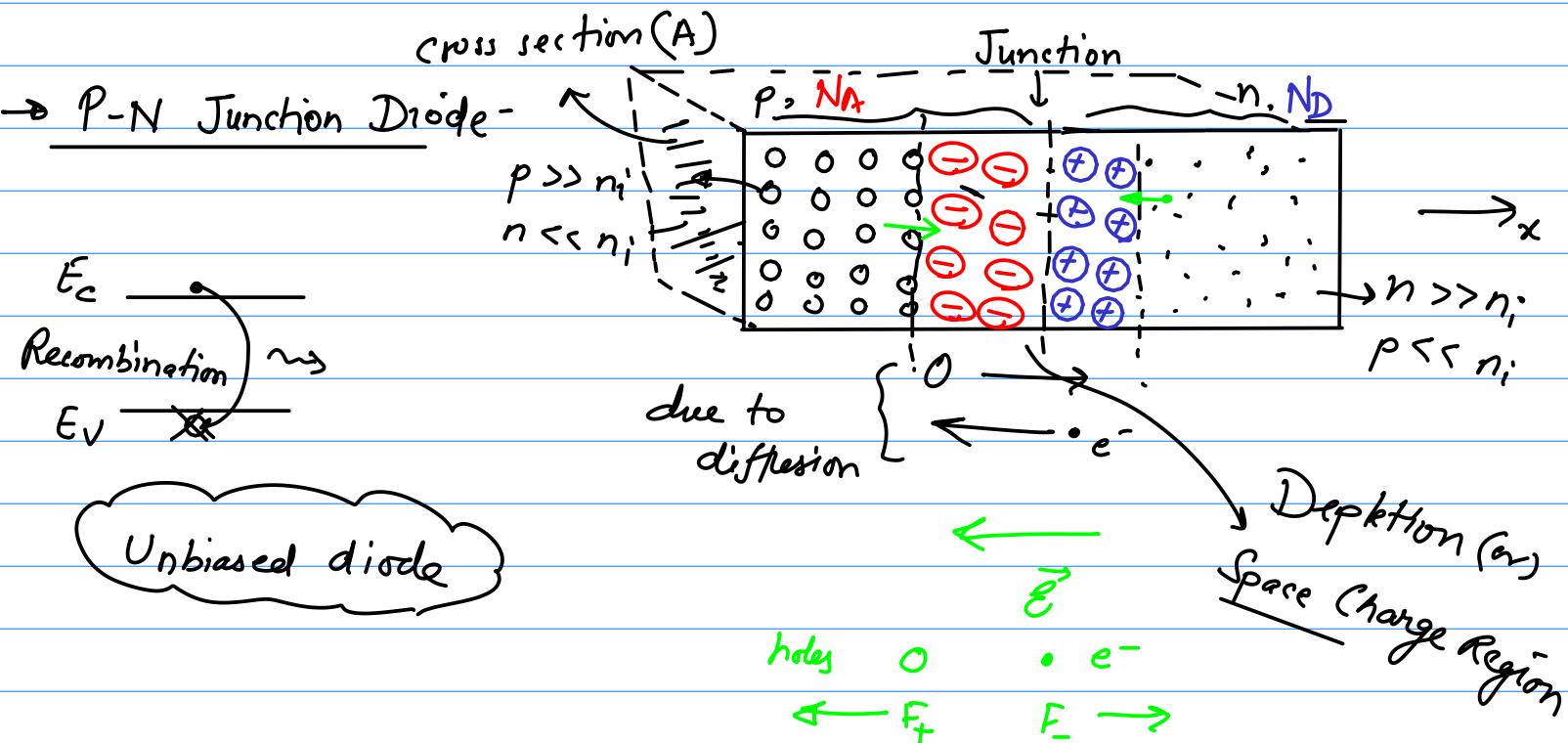
$$\approx 26 \text{ mV at room temp}$$

$D$  = Diffusion constant  
( $\text{cm}^2/\text{s}$ )

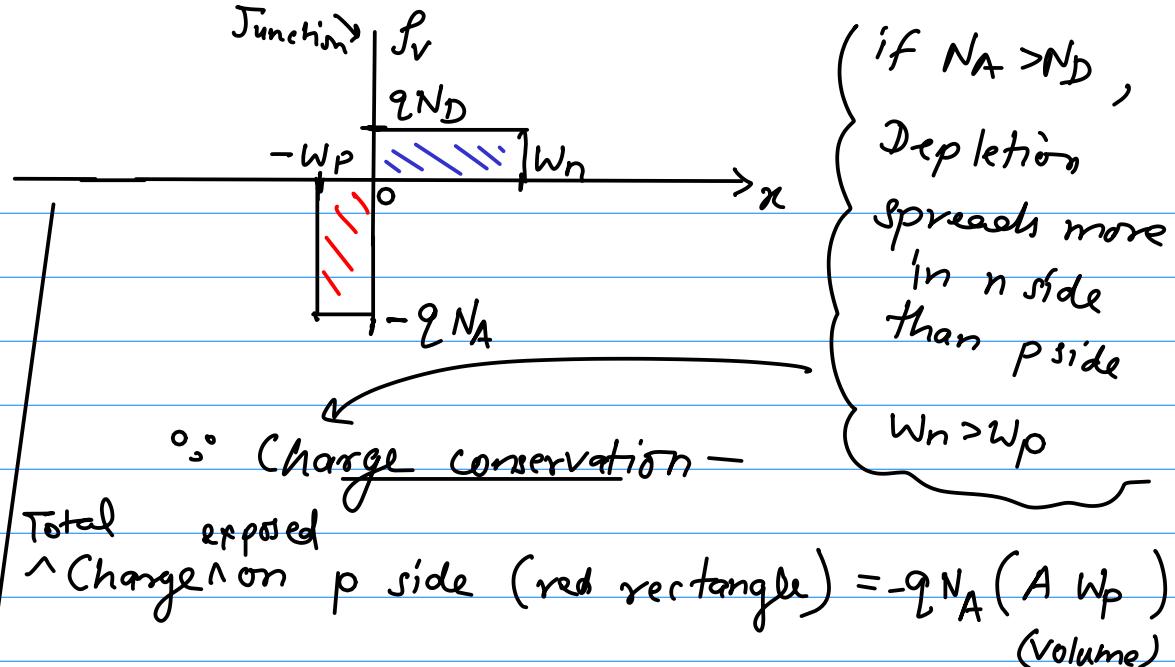
$\mu$  = mobility ( $\text{cm}^2/\text{Vs}$ )

$$\frac{kT}{q} = V_T \approx 26 \text{ mV at room temp.}$$

↓  
Thermal voltage



$\rho_V$  = Volume Charge density ( $C/cm^3$ )



Total charge exposed on n side =  $+qN_D(A W_n)$   
by charge conservation →

$$|-qN_A A W_p| = |+qN_D A W_n|$$

$$\Rightarrow N_A W_p = N_D W_n \quad ** \quad (\text{Red rectangle area}) = (\text{Blue Rect. area})$$

→ Plot  $\vec{E}$  &  $V$  in this device - "Poisson's Equation"

$$\nabla^2 V = -\frac{\rho_V}{\epsilon}$$

$$\frac{d^2 V}{dx^2} = -\frac{\rho_V}{\epsilon}$$

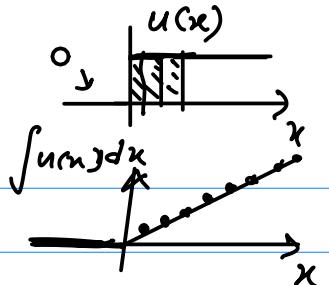
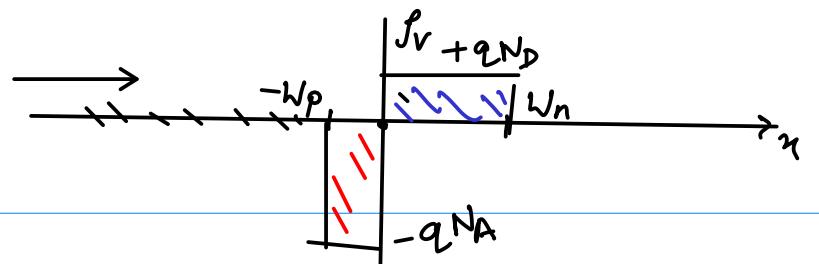
$$\frac{d}{dx} \left( \frac{dV}{dx} \right) = -\frac{\rho_V}{\epsilon}$$

Also,

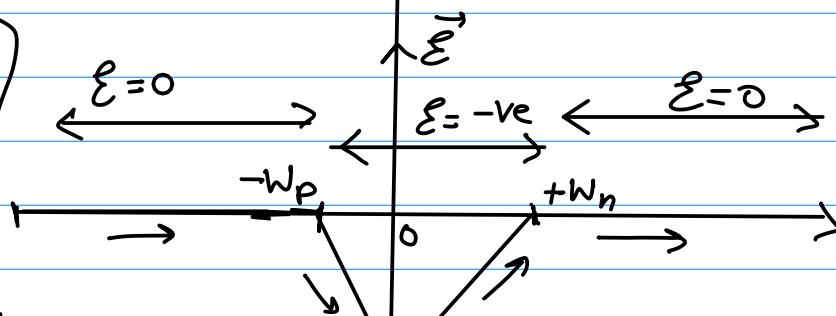
$$\vec{E} = -\frac{dV}{dx}$$

$$\Rightarrow \frac{dE}{dx} = \frac{\rho_V}{\epsilon}$$

$$\frac{d\epsilon}{dx} = \frac{f_V}{\epsilon}$$



$$So, \epsilon = \int f_V dx$$

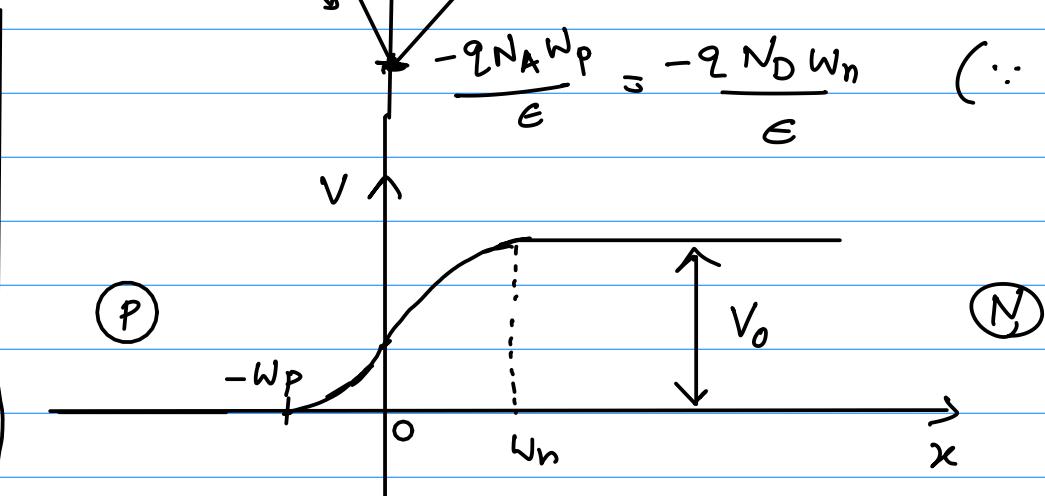


$$V(x) = ?$$

$$\epsilon = -\frac{dV}{dx}$$

$$V = - \int \epsilon dx$$

Let  $\overset{\text{metal}}{\Delta} p$  contact be at  $V = 0$  (reference)



\*  $V_0$  = Built-in Potential.

\* Naturally appears (without external bias)

\*  $V_0$  is -ve of total area under  $\vec{\epsilon}$  curve.

$$\text{Area under } \vec{\epsilon} = \frac{1}{2} \times (\text{Altitude}) \times (\text{base})$$

$$= \frac{1}{2} \times \left( -\frac{qNA w_p}{\epsilon} \right) \times (w_p + w_n)$$

$$\text{or} \quad = \frac{1}{2} \left( -\frac{qND w_n}{\epsilon} \right) (w_p + w_n)$$

$$So, V_0 = \frac{1}{2} \left( \frac{qNA w_p}{\epsilon} \right) (w) = \frac{1}{2} \left( \frac{qND w_n}{\epsilon} \right) (w)$$

Where  $w = w_p + w_n = \text{Total Depletion width.}$

We have

$$W = W_p + W_n \quad \text{--- (1)}$$

$$N_A W_p = N_D W_n \quad \text{--- (2)} \quad (\text{Charge Conservation})$$

Solving for  $W_p$  &  $W_n \rightarrow$

$$W_p = \left( \frac{N_D}{N_A + N_D} \right) W$$

&

$$W_n = \left( \frac{N_A}{N_A + N_D} \right) W$$

$$W_p \propto N_D$$

$$W_n \propto N_A$$

So, if  $N_A > N_D$  then  $W_n > W_p$

Replacing  $W_p$  or  $W_n$  in  $V_0$  expression,

$$V_0 = \frac{1}{2} \left( \frac{q N_A}{\epsilon} \right) \left( \frac{N_D}{N_A + N_D} \right) W \quad \uparrow W_p$$

$$V_0 = \frac{q}{2\epsilon} \left( \frac{N_A N_D}{N_A + N_D} \right) W^2$$

} Relation between  $V_0$  &  $W$

Solve for  $W$

$$W = \sqrt{\frac{2\epsilon}{q} \left( \frac{N_A + N_D}{N_A N_D} \right) V_0}$$

$$W = \sqrt{\frac{2\epsilon}{q} \left( \frac{1}{N_A} + \frac{1}{N_D} \right) V_0}$$

\*\* [used to find  $W$   
if  $N_A$ ,  $N_D$ ,  $V_0$   
are known]

$V_0$  can be found from  $\rightarrow$   
(kelvin)

where  $\frac{kT}{q} = V_T = \frac{T}{11600} = 26\text{mV}$   
(at 300K)

$$V_0 = \frac{kT}{q} \ln \left( \frac{N_A N_D}{n_i^2} \right)$$

\*\*

$$V_0 = \frac{kT}{q} \ln\left(\frac{N_A N_D}{n_i^2}\right) = \frac{kT}{q} \ln\left(\frac{N_D}{\{n_i^2/N_A\}}\right) \xrightarrow{\text{maj. } e^- \text{ conc. on } n\text{-side } (n_n)} \\ \downarrow \text{minority } e^- \text{ conc. on } p\text{-side } (n_p)$$

So,

$$V_0 = \frac{kT}{q} \ln\left(\frac{n_n}{n_p}\right) = \frac{kT}{q} \ln\left(\frac{P_p}{P_n}\right)$$

→ Revisiting EBD -

Let  $e^-$  in cond. band have total energy  $E$

$$E = P.E. + K.E.$$

Where

$$P.E. = E_c - E_{ref}$$

$$\text{So, } K.E. = E - P.E. = E - (E_c - E_{ref})$$

Let  $E_{ref} = 0$

then  $K.E. = E - E_c$  (height of  $e^-$  over  $E_c$ )  
 $\hookrightarrow (\frac{1}{2}mv^2)$

\*  $e^-$  at  $E_c$  has zero velocity ( $\because KE=0$ )

\* Higher an  $e^-$  in cond. band, faster it moves.

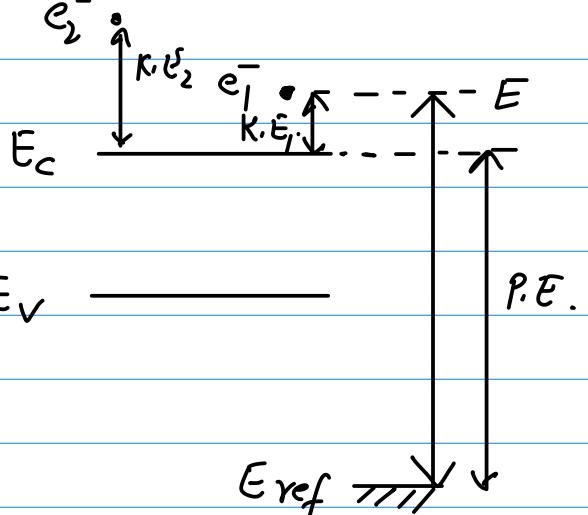
\*  $E_c - E_{ref} = \boxed{P.E. = E_c}$  (if  $E_{ref} = 0$ )

\*  $P.E. = (\text{charge}) \times (\text{Potential})$

in EBD, vert. axis is  $e^-$  energy

So,  $E_c = -qV$

where  $-q = e^-$  charge



## EBD of p-n junction diode -

$$E_c = -qV$$

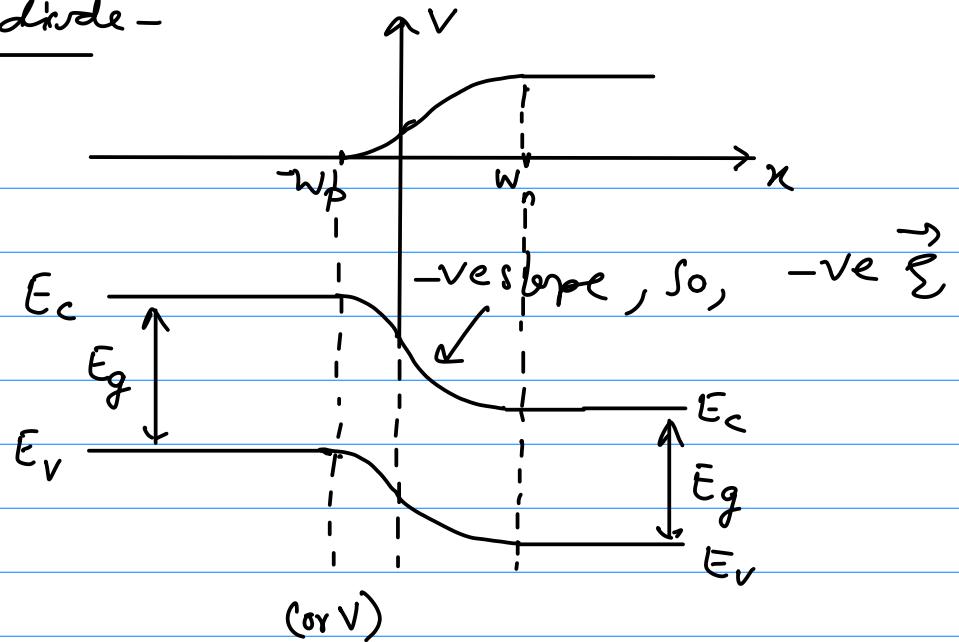
$$\vec{\mathcal{E}} = -\frac{dV}{dx}$$

$$\mathcal{E} = -\frac{d}{dx} \left( \frac{-1}{q} E_c \right)$$

$$\mathcal{E} = \frac{1}{q} \frac{dE_c}{dx}$$

So,

$$E_c = q \int \mathcal{E} dx$$



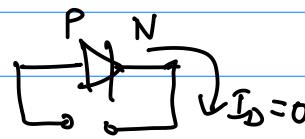
\* if  $\mathcal{E}$  is known then  $E_c$  can be found.

\*  $E_v$  will be  $E_g$  below  $E_c$

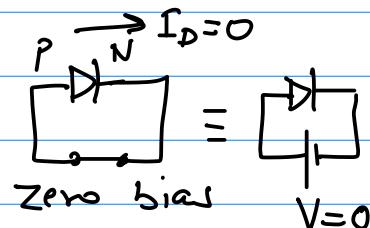
\*  $\vec{\mathcal{E}}$  is always in the direction of rise of  $E_c$

- Biasing a P-N Junction -
- (i) No Bias } Equilibrium,  $I_D = 0$
  - (ii) Zero Bias } Equilibrium,  $I_D = 0$
  - (iii) Forward Bias } Non Equilibrium,  $I_D \neq 0$
  - (iv) Reverse Bias }

i & ii) Zero & No bias -

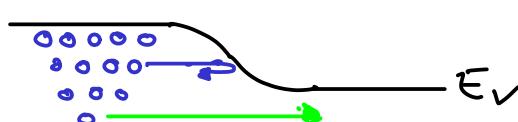
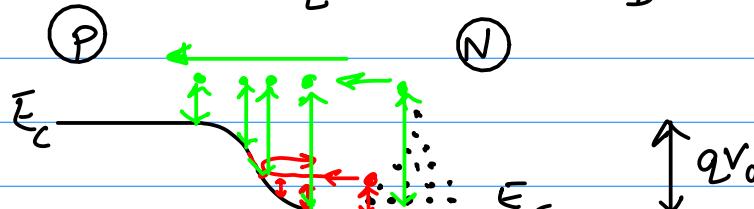


No bias



zero bias

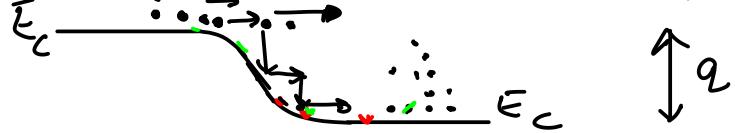
Diode under Eq/bm. &  $I_D = 0$



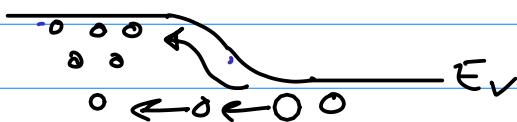
\*  $e^-$  conc. reduces exponentially as we go up in cond. band.

\* hole conc. reduces exponentially as we go down below  $E_v$ .

from P side, min. e's if come into dep region, they get swept away to N side



Similarly for <sup>min.</sup> holes on N-side.



carriers can roll down the hill

- \* Under Equilibrium, No. of min. e's going from P-N (drift) is same as no maj. e's going from N-P over the barrier (diffusion).

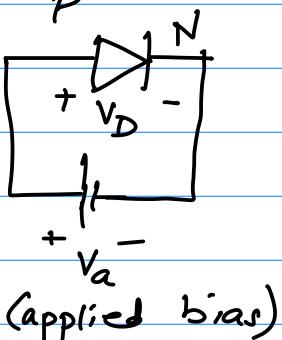
$$\text{So, } J_n = J_{n \text{ diff.}} + J_{n \text{ drift}} = 0$$

(+ve)                  (-ve)

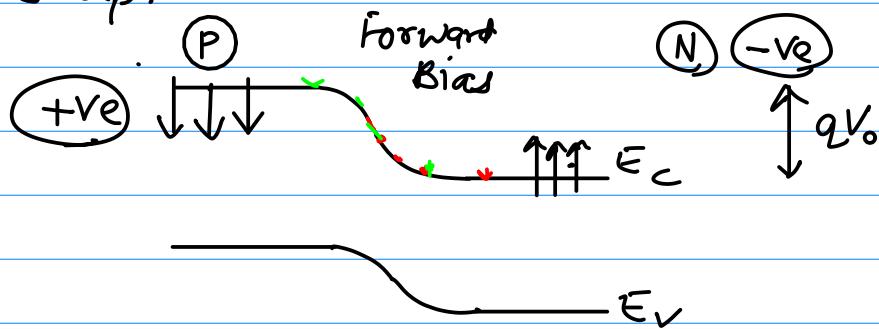
- \* Similarly  $J_p = J_{p \text{ diff}} + J_{p \text{ drift}} = 0$

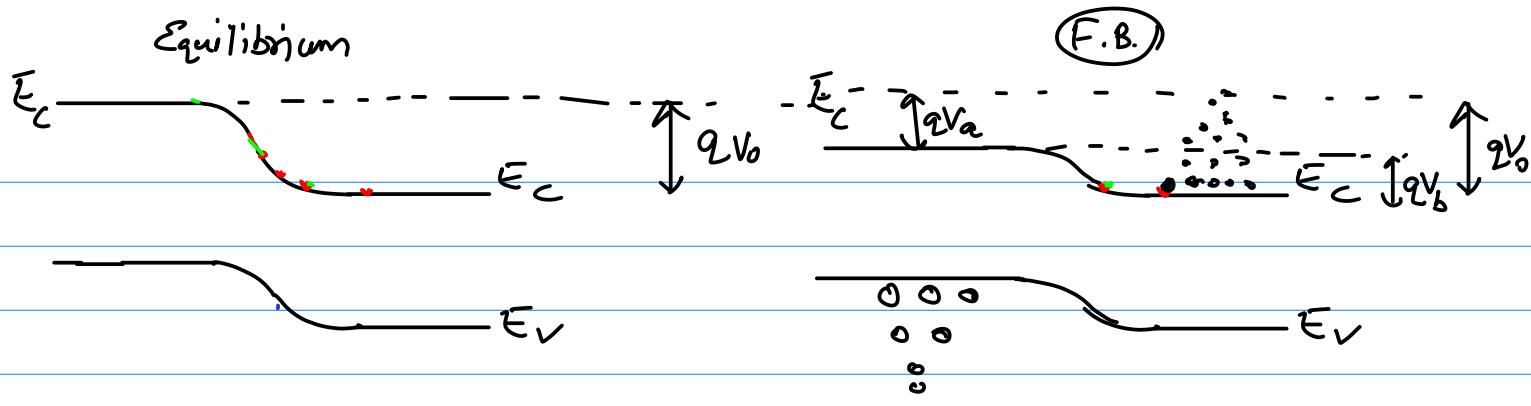
$$\text{So, } J = J_n + J_p = 0 \quad [\text{zero bias \& no bias}]$$

- (iii) Forward Bias - \* The side with +ve (or higher pot.) moves down in EBD.  $\because E_C = P.E. = -qV$  if  $V$  (+ve), -ve P.E. gets added. If  $V$  = -ve, +ve P.E. is added & EBD moves up.



$$\text{here, } V_D = V_a$$





If N side contact (metal-S.C. contact) is taken as reference, then E<sub>C</sub> on side can be taken at same level. w.r.t. it, P side E<sub>C</sub> moves down by an amount of  $qV_D = qV_A$

- \* By F.B., barrier height reduces.

$$qV_b = qV_0 - qV_D$$

- \* Now there are several (exponential) maj. carriers on both sides that can go over the barrier.
- \* But minority carriers crossing to other side are still same in number. ∵ height of barrier never mattered to them
- \* So, there is imbalance. Min. es drifting from P to N can no longer cancel Maj. es diffusing from N to P. So,  $J_n = \text{non zero}$  (+ve x dir. ∵ e<sup>-</sup> N to P)
- \* Similarly due to imbalance in hole motion  $J_p = \text{non zero}$  (+ve x dir. ∵ holes, P to N)
- \* So,  $J = J_n + J_p = \text{non zero}$  (from P to N)



\*

$$I_D \propto \exp(V_D)$$

$$I_D = I_0 \left( e^{\frac{qV_D}{\eta kT}} - 1 \right) \quad *$$

$\eta$  = Ideality factor. It should be 1 ideally but practically  $1 < \eta$

Typically  $1 < \eta \leq 2$

$$\frac{kT}{q} = V_T = \frac{T}{11,600} \text{ (Kelvin)} \simeq 26 \text{ mV at } 300 \text{ K.}$$

\* if  $V_D \gg 3V_T$  then  $e^{\frac{V_D}{\eta V_T}} \gg 1$

&

$$I_D = I_0 \exp\left(\frac{V_D}{\eta V_T}\right)$$

\*  $I_0$  = Reverse Saturation Current or thermal current  
Min. carrier current

$$I_0 = qA \left[ \frac{D_p}{L_p} P_{n_0} + \frac{D_n}{L_n} n_{p_0} \right]$$

$D_p, D_n \rightarrow$  Diffusion constants

$L_p \rightarrow$  minority hole diffusion length (in n-type s.c.)

$L_n \rightarrow$  min. e- diffusion length (in p-type s.c.)

Min. Diffusion Length (L)  $\rightarrow$  Average distance for which a min. carrier can diffuse into a seq of maj. carriers, before it gets recombined.

$P_{n_0} \rightarrow$  min. hole conc. on n side at equilibrium

$$P_{n_0} = \frac{n_i^2}{N_D}$$

$n_{p_0} \rightarrow$  min. e<sup>-</sup> conc. on p-side at equilibrium

$$n_{p_0} = \frac{n_i^2}{N_A}$$

\*  $\sqrt{D_p L_p} = \tau_p$  &  $\sqrt{D_n L_n} = \tau_n$

where  $\tau_p$  &  $\tau_n$  are minority carrier lifetime for holes & e<sup>-</sup>s resp.

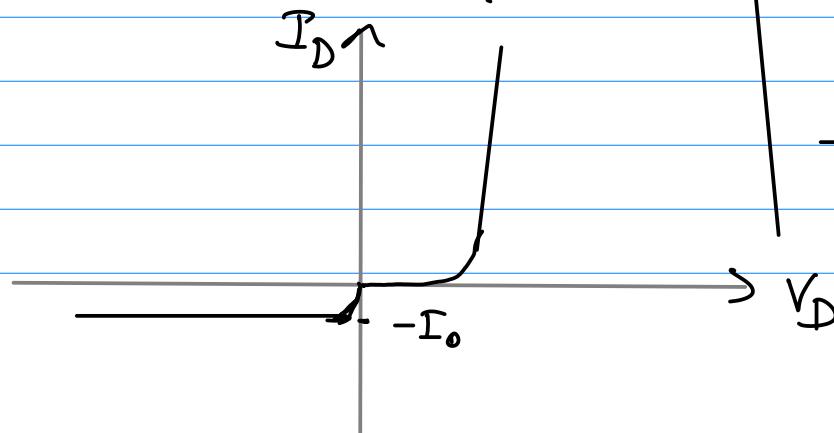
Mn. carrier Lifetime - Average lifetime of min. carriers from generation to recombination.

→ IV characteristics of P-N J<sup>n</sup> diode -

$$I_D = I_0 \left( \exp\left(\frac{V_D}{nV_T}\right) - 1 \right)$$

$$\frac{V_D}{nV_T} \gg 1 \quad (V_D = +ve)$$

$$I_D = I_0 \exp\left(\frac{V_D}{nV_T}\right)$$



If  $V_D = -ve$   
exp. term become  
negligible  
 $\therefore I_D = -I_0$

# Depletion Width under F.B -

$$W = \sqrt{\frac{2e}{q} \left( \frac{1}{N_A} + \frac{1}{N_D} \right) (V_b)}$$

↓  
actually barrier potential  
(at equil.,  $V_b = V_0$ )

\*  $V_b = V_0 - V_D$

So,  $W = \sqrt{\frac{2e}{q} \left( \frac{1}{N_A} + \frac{1}{N_D} \right) (V_0 - V_D)}$  \*

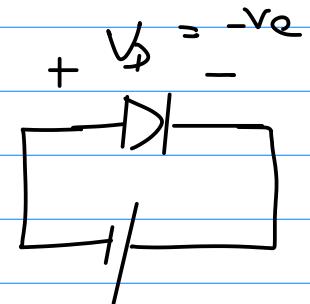
if  $V_D = +ve$  (F.B.),  $W < W_0$

$W_D = W$  at equilibrium

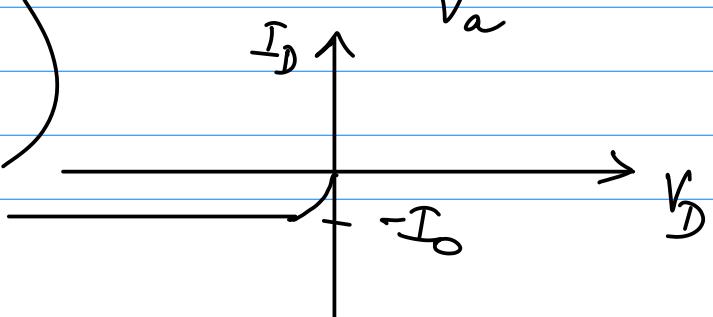
If  $V_D = -ve$  (R.B.),  $W > W_0$

→ Reverse Bias P-N J^n -  $V_D = -ve$

$$I_D = I_0 \left( \exp \left( \frac{V_D}{nV_T} \right) - 1 \right)$$



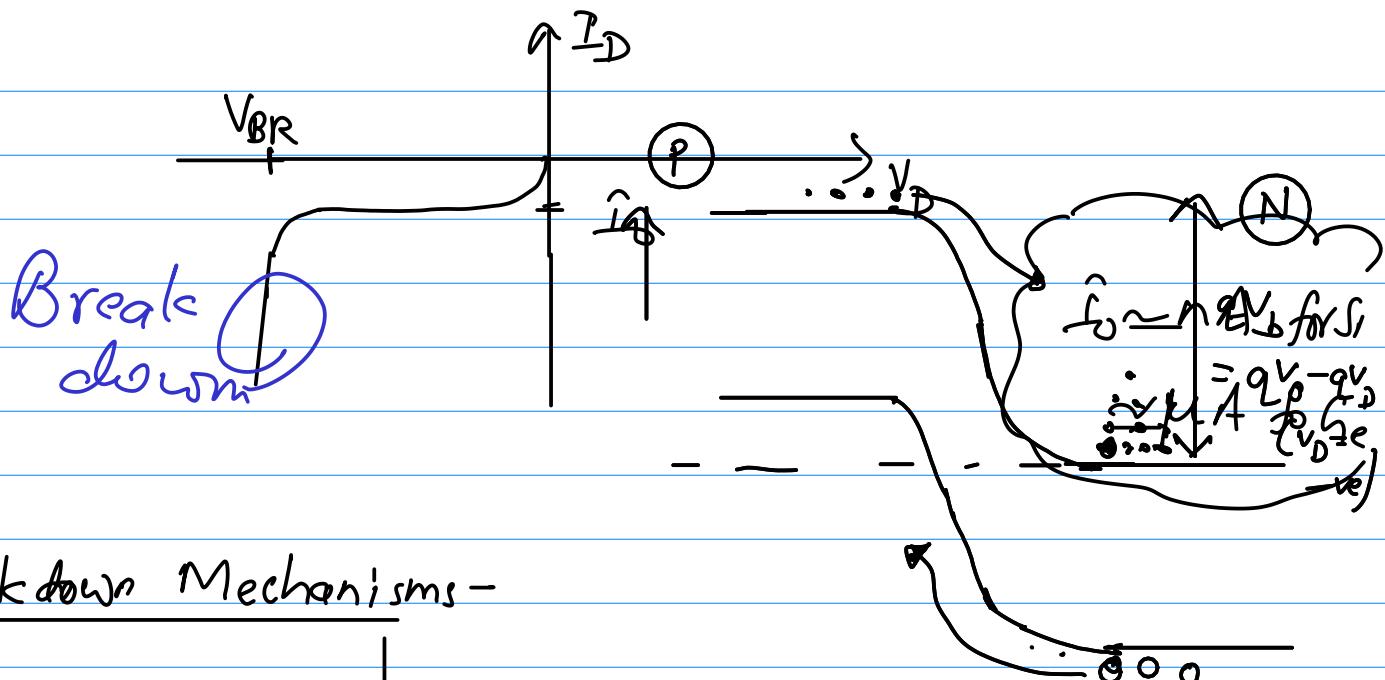
$$= I_0 \left( \exp \left( \frac{1}{\frac{nV_T}{V_D}} \right) - 1 \right)$$



as  $|V_D| \rightarrow \infty$ ,

$$I_D = I_0 (0 - 1)$$

\* If we keep  $\uparrow$  R.B., Diode breaks down

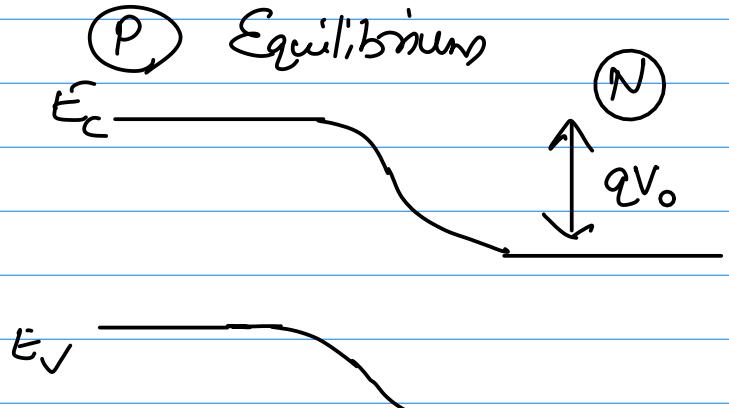


### → Breakdown Mechanisms -

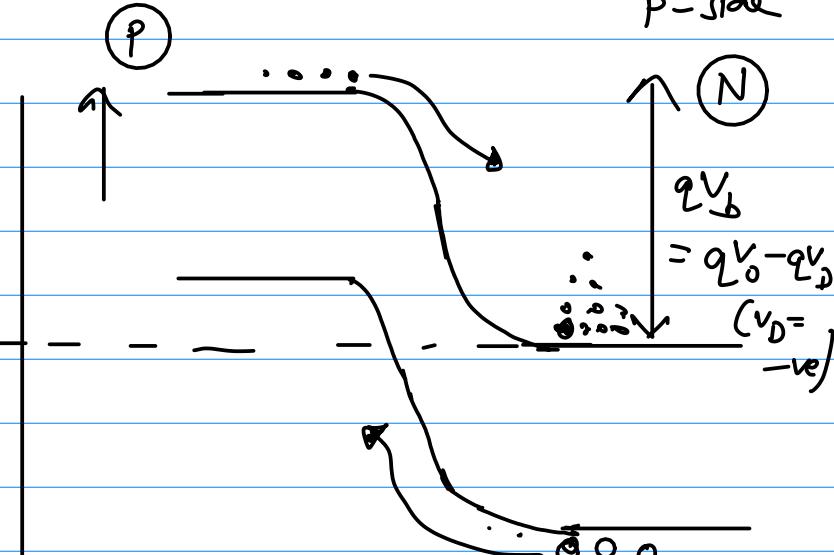
Avalanche  
Breakdown

Zener Breakdown

### → R.B. E.B.D.

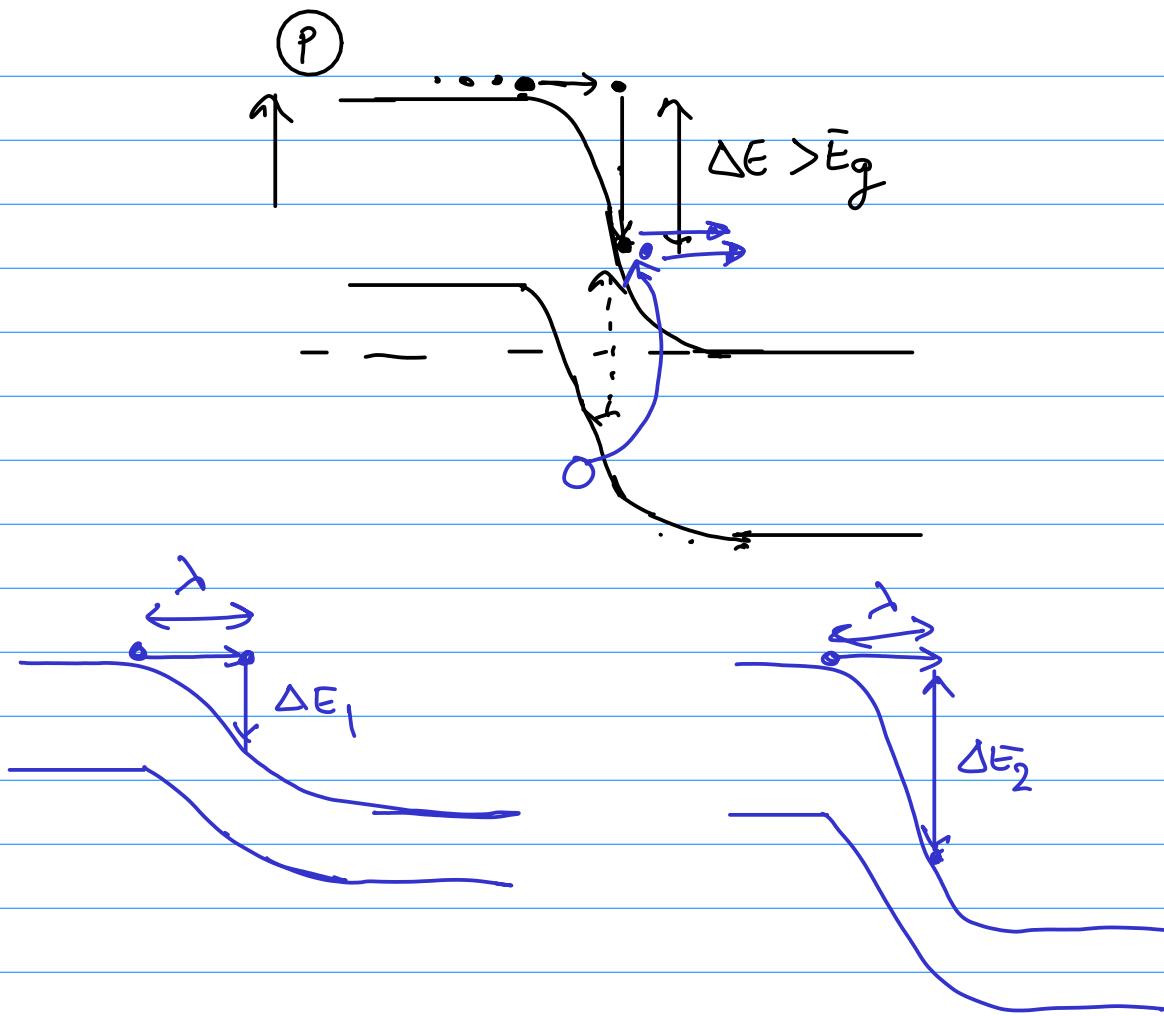


R.B.  $\rightarrow$  -ve pot at p-side



Cond. is only due to  
min carriers rolling down  
the potential hill

# Avalanche - (Impact Ionisation)

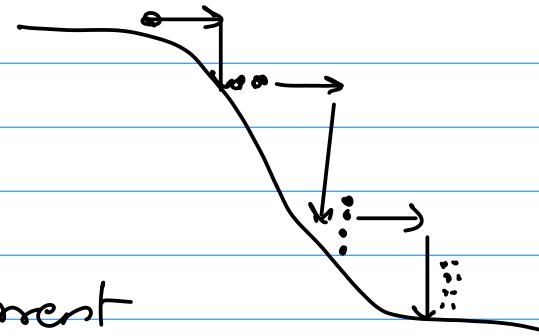


$$\Delta \tilde{E}_2 > \Delta E_1$$

- \* ↑ Steepness of band in dep. Region.  $\Delta E \uparrow$  for same  $\lambda$  (mean free path  $\rightarrow$  avg. dist b/w 2 collision  $\rightarrow$  free path)
- \* Steepness / slope of  $E_C = \vec{\varepsilon}$  (electric field)
- \* So, ↑  $\varepsilon$  in dep. ↑  $\Delta E$  on collision

So, chances of Impact Ionisation are more if  $\vec{\varepsilon}$  is more.

- \* If dep region is wide (large  $W$ ), then a single  $e^-$  could undergo several I.P. events (say  $m$  events). So every  $e^-$  causes generation of  $m$  new EHPs as it passes  $\omega$ .



- \* Avalanche happens.  
= & a large R.B. current flows in the device,
- \* for Avalanche breakdown,  $W$  should be large i.e. it happens if dopings are low ( $W \propto \frac{1}{N}$ )
- \* But large  $\vec{\varepsilon}$  is also needed. So it happens for large R.B. voltages ( $V_{BR} = \text{large}$ )  
 $(\because \text{under R.B.}, |V_D| \uparrow \rightarrow \vec{\varepsilon} \uparrow, V_b \uparrow)$

- $\rightarrow$  Zener breakdown - happens due to "Tunneling"  
 (for thin barriers)  
 \* It happens if dopings are large.  
 (small  $W$ )  
 $(W \propto \frac{1}{N}, \text{large } N)$   
 \* It happens at smaller  $V_{BR}$  as compared to Avalanche breakdown.

\* as  $T \uparrow$ ,  $V_{BR}$  (avalanche) increases (+ve temp coeff.)

\* as  $T \uparrow$   $V_{BR}$  (zener) decreases (-ve temp coeff.)

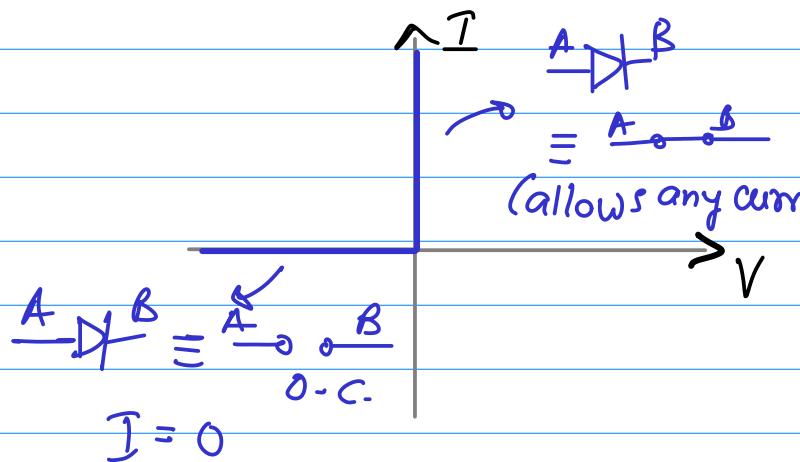
→ Diode circuits -

why! → Rectification

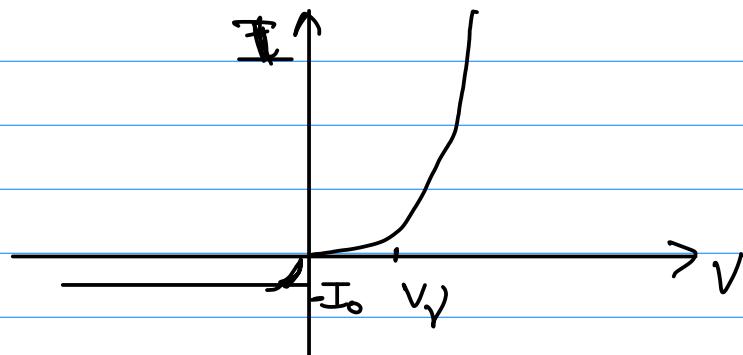
uni-directional conduction

\* What we want from diode is

\* Ideal Rectifier? →



Practically →



In ckt's, a diode can be replaced by a model.

→ Large Signal Model of diode -

large signal  $\rightarrow$  DC bias vol.

can be changed

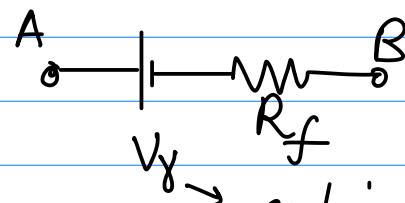
small signal  $\rightarrow$  (signal to be processed + bias  $\downarrow$  (large DC))  $\rightarrow$  applied (large signal) to device

<< large signal



Replaced by

(i) F.B. case



(ii) R.B. case



$R_r$  = Reverse Resistance

(large)

$(R_r \rightarrow \infty)$

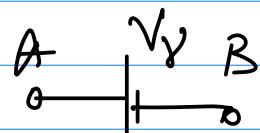


↓ Simpler

$R_f$  = forward bias resistance

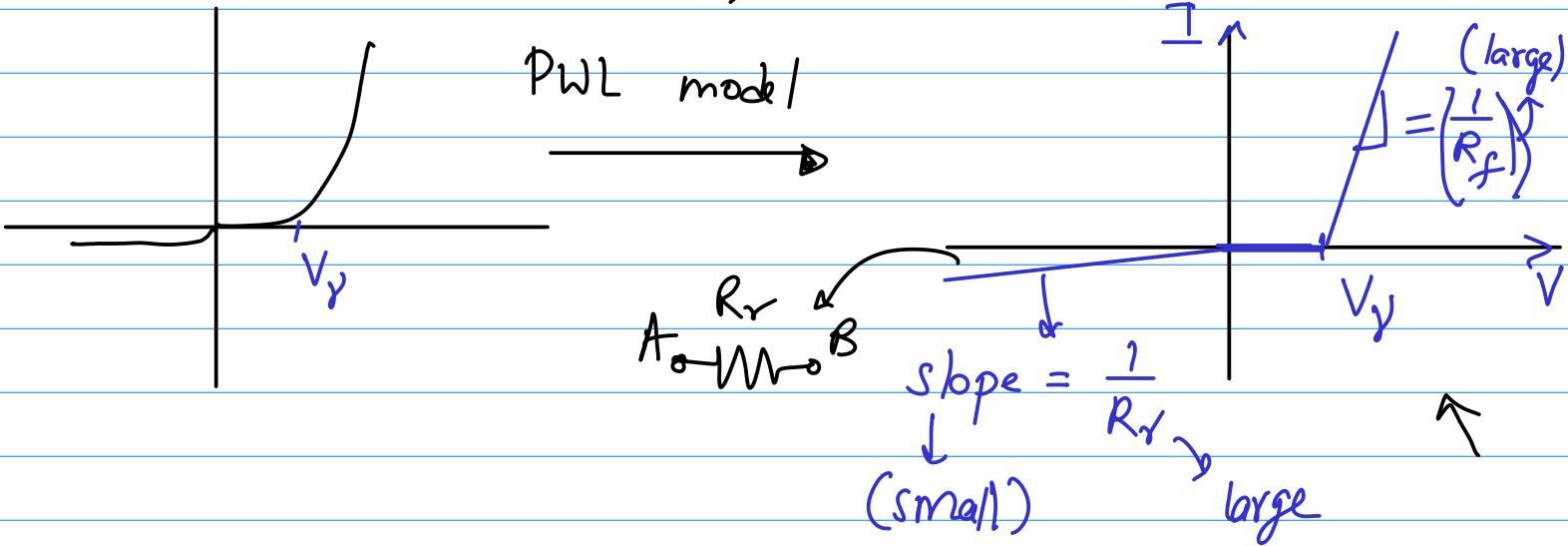
(small)

even simpler model  $\rightarrow$

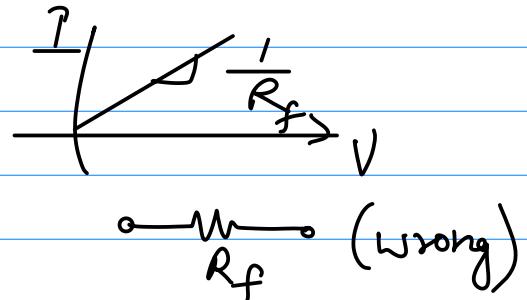


$(R_f \rightarrow 0)$

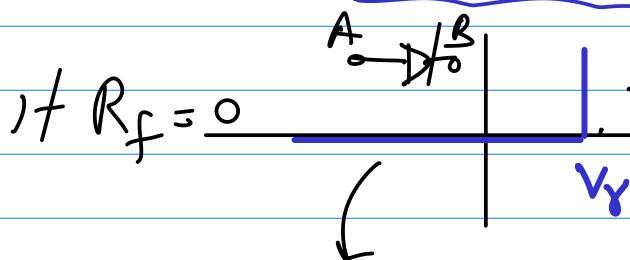
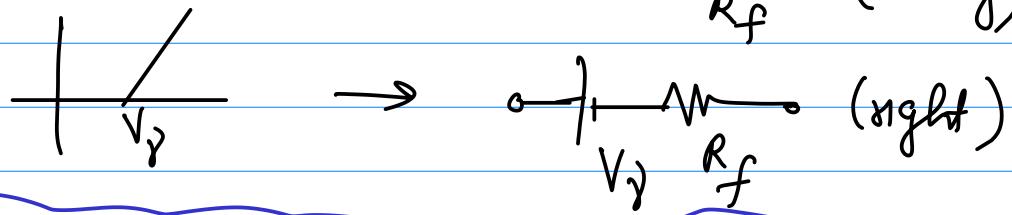
Graphically (Piece-wise Linear Model)  
(PWL)



from PWL model, F.B.  $\rightarrow$



but actually,



$A \xrightarrow[0.2V]{\text{O.C.}} B$

Simpler model

\* for Si,  $V_y \approx 0.7 V$

Ge  $V_y \approx 0.2 V$

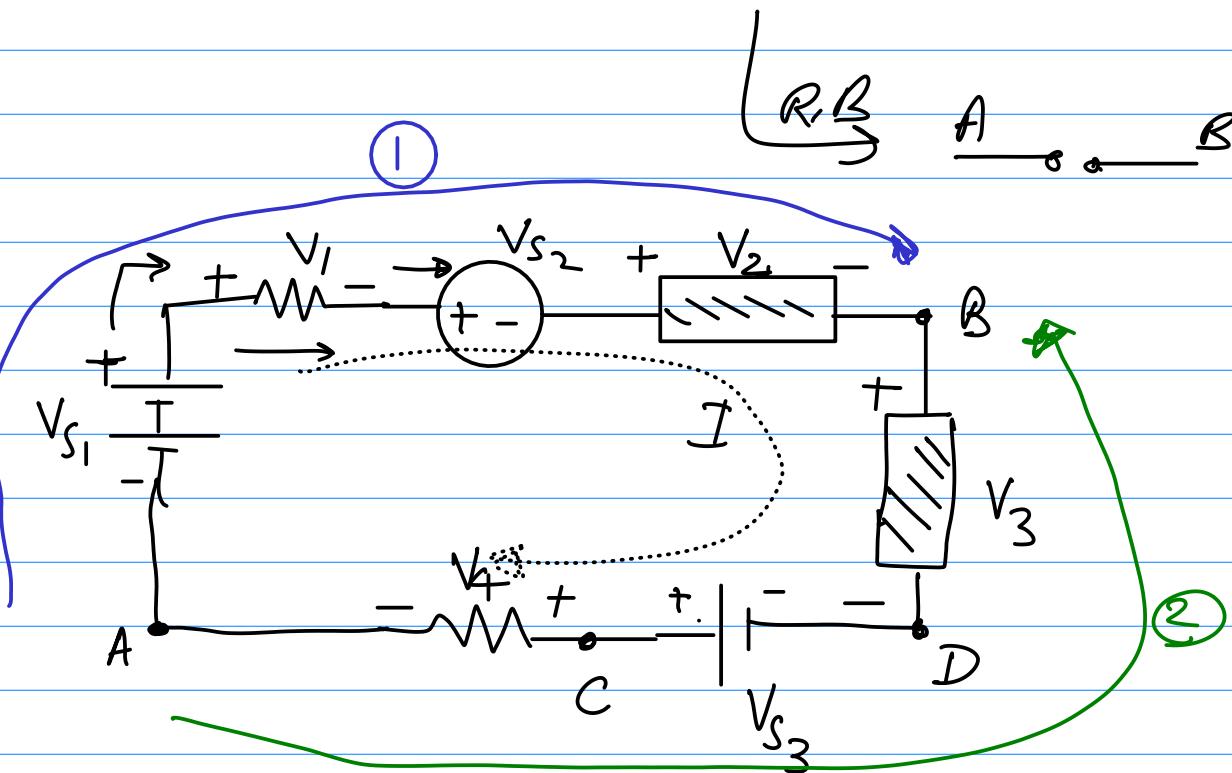
$$\frac{dV_y}{dT} = -2.5 \text{ mV/}^\circ\text{C}$$

→ If ideal diode is mentioned,

$$V_D = 0$$



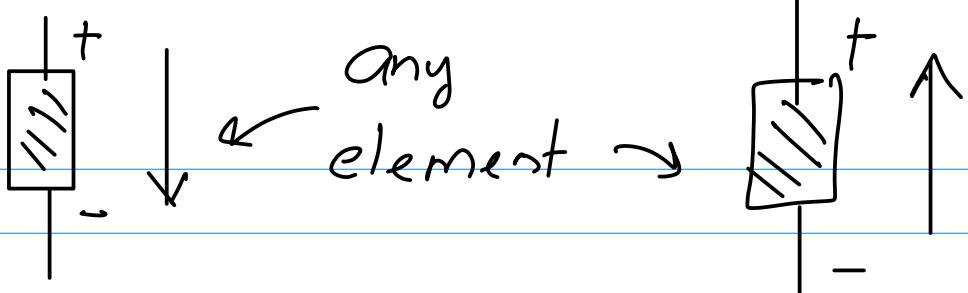
→ KVL:



(1) KVL can be applied from any node to any other node in circuit (loop is not necessary, it is only a special case where the starting & end points are same)

(2) You can assume any dir. for current & any polarities for all the potential drops (voltage or pot. diff.)

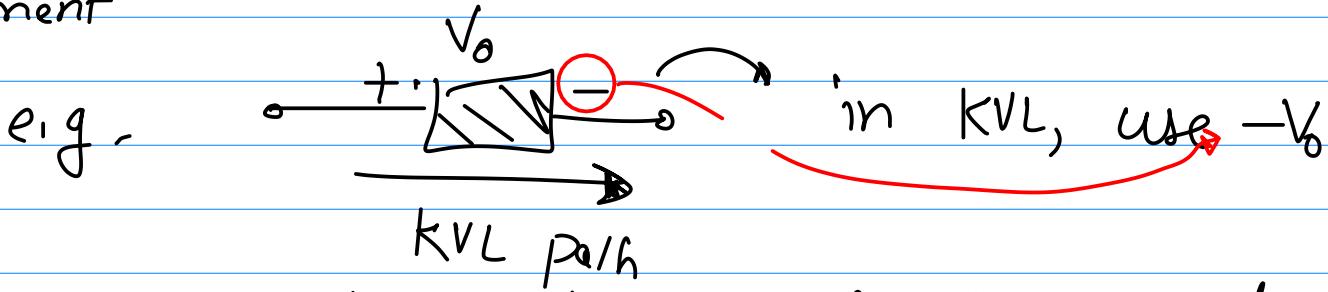
[for resist. I always flows from higher to lower pot. through the resistance]



(absorbing/consuming power)

(Delivering power)

(3) To write KVL, start with pot. at beginning node (e.g.  $V_A$ ). Then write every pot. drop along the path with sign taken from the terminal where path exits the element



Finally, equate it all to potential at end node -

example path ① →

$$V_A + V_{S_1} - V_1 - V_{S_2} - V_2 = V_B$$

(KVL) — ①

Now Pot. diff b/w B & A =  $V_B - V_A = V_{BA}$

from ①,

$$V_B - V_A = V_{BA} = V_{S_1} - V_1 - V_{S_2} - V_2$$

— ②

Along path ② -

$$V_A + V_4 - V_{S_3} + V_3 = V_B \quad \text{--- } ③$$

$$V_B - V_A = V_{BA} = V_4 - V_{S_3} + V_3 \quad \text{--- } ④$$

from ② & ④

$$V_4 - V_{S_3} + V_3 = V_{S_1} - V_1 - V_{S_2} - V_2 \quad \text{--- } ⑤$$

Along loop  $\rightarrow (A \rightarrow B \rightarrow D \rightarrow C \rightarrow A)$

$$V_A + V_{S_1} - V_1 - V_{S_2} - V_2 - V_3 + V_{S_3} - V_4 = V_A$$

$$\boxed{V_{S_1} - V_1 - V_{S_2} - V_2 - V_3 + V_{S_3} - V_4 = 0} \quad \text{--- } ⑥$$

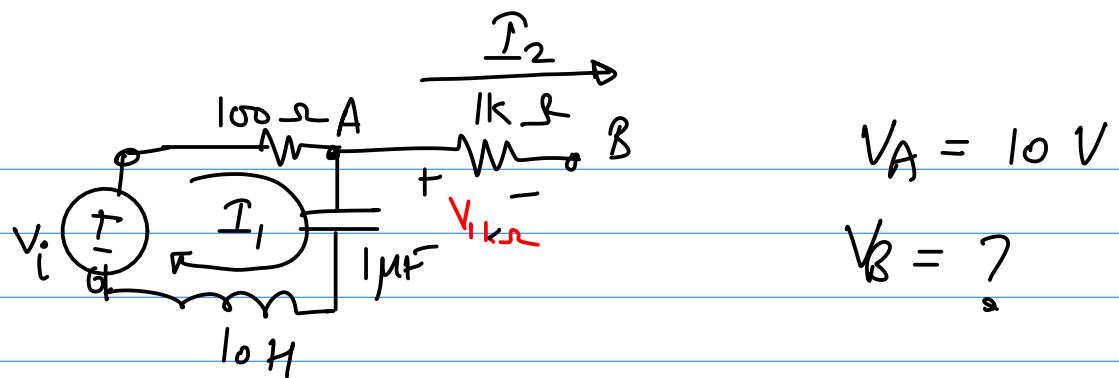
e.g. ⑤ & ⑥ are same !!

example -  $V_A$  is known, & we want  $V_D$

use KVL from A to D

$$V = V_A + V_4 - V_{S_3}$$

Ex problem



$$\text{Use KVL} - V_A - V_{1k\Omega} = V_B$$

$$10 - V_{1k\Omega} = V_B$$

?  $\because$  circuit at B is not complete,  $I_2 = I_{1k\Omega} = 0$

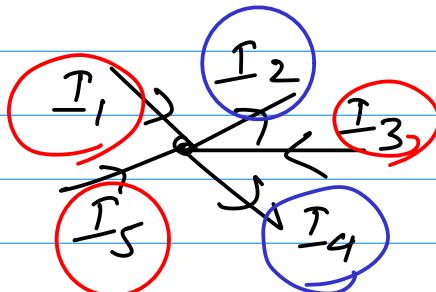
$$\text{So, } V_{1k\Omega} = R \times I = 1 \text{ k}\Omega \times 0 = 0$$

So,

$$10 - 0 = V_B \Rightarrow$$

$$V_B = V_A = 10 \text{ V}$$

KCL



(i) Assume dir. of unknown currents.

opposite signs

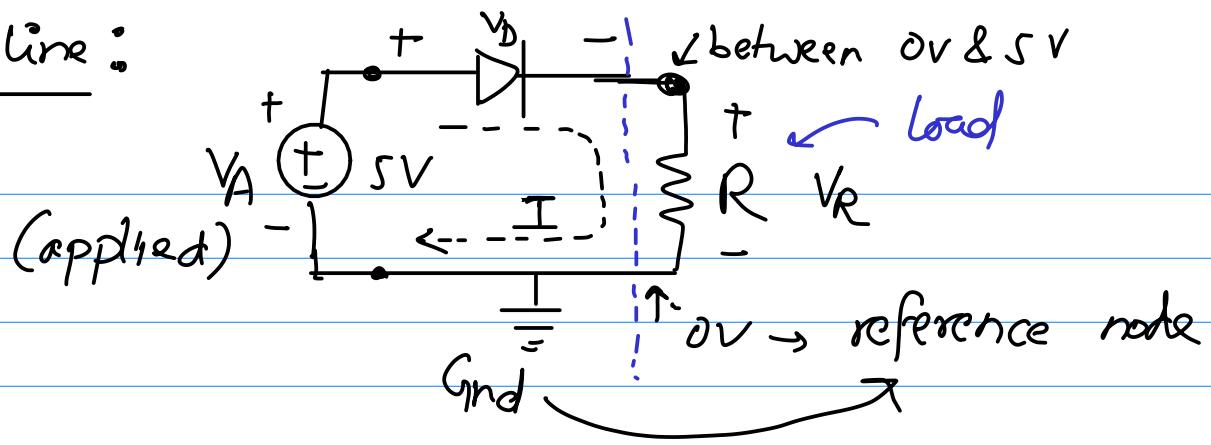
(ii) Use + for incoming currents & outgoing currents in algebraic sum.

Let incoming currents = +ve, outgoing = -ve

$$I_1 - I_2 + I_3 - I_4 + I_5 = 0$$

KCL

→ Load line:



Apply KVL in the loop-

$$+V_A - V_D - V_R = 0 \Rightarrow V_A = V_D + V_R$$

$$V_R = IR \quad (\text{Ohm's law})$$

$$V_A = V_D + IR \Rightarrow I = -\frac{1}{R} V_D + \frac{1}{R} V_A \quad \boxed{\textcircled{1}}$$

(Load line)

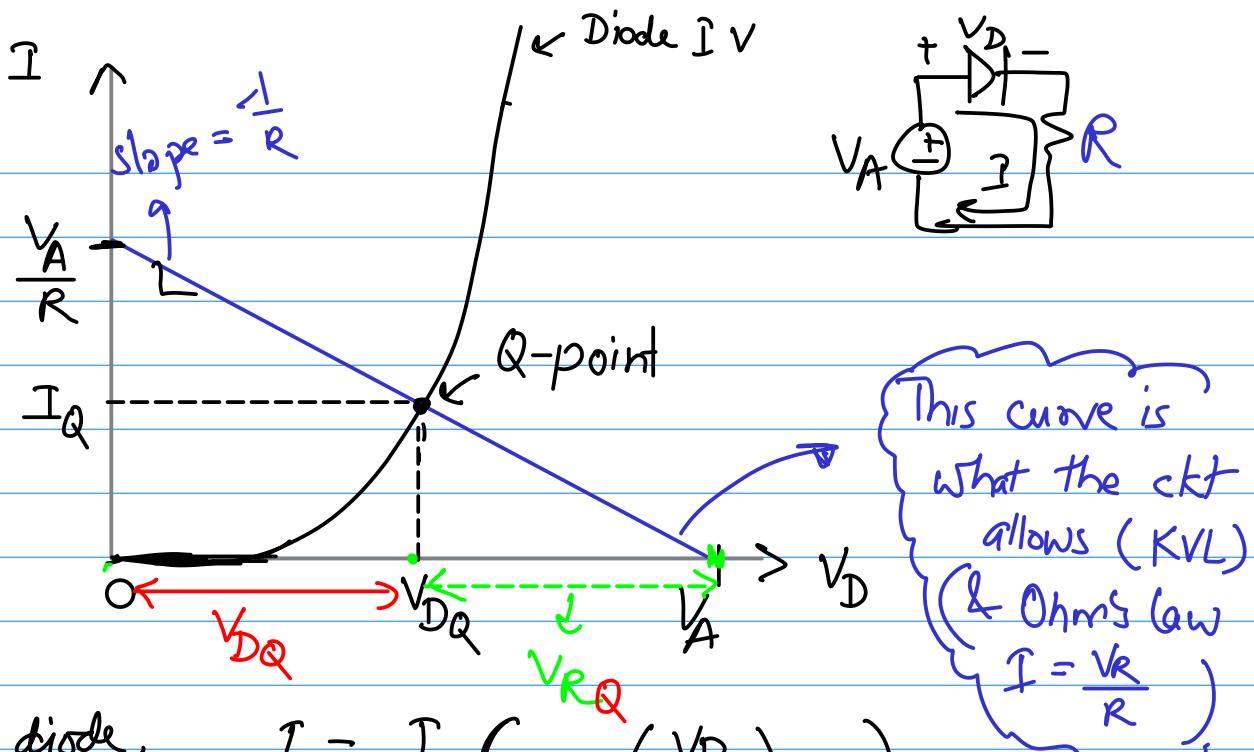
\* Eq① relates ckt current  $I$  to diode vrf  $V_D$  -  
(assuming  $R$  &  $V_A$  to be constant)

\* Eq ① is a straight line ( $y = mx + c$ )

$$\text{So, slope} = -\frac{1}{R} \quad (\text{ve})$$

$$\text{vert. axis intercept} = \frac{V_A}{R}$$

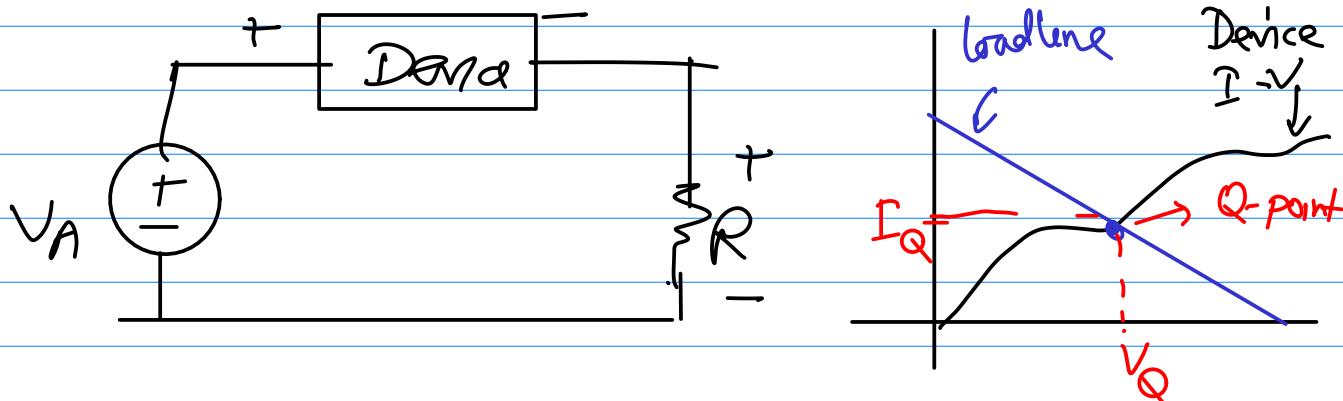
\* Slope of this line changes with  $R$  (load  
in this ckt)



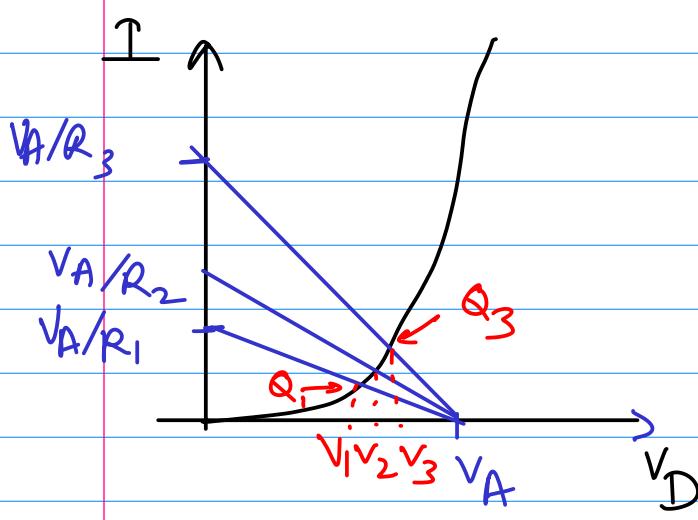
This curve is what the ckt allows (KVL) (& Ohm's law  $I = \frac{V_R}{R}$ )

- \* But for diode,  $I = I_0 \left( \exp\left(\frac{V_D}{nV_T}\right) - 1 \right)$
- \* Both curves should be satisfied.
- \* Q-point = Operating point (Actually the ckt operates at this  $\rightarrow$  current ( $I_Q$ ) & this diode vol. ( $V_{DQ}$ ))
- \* Load line concept is applicable to any device ckt. to find operating point.
- \* Q-point  $\rightarrow V_{DQ}$  is the vol that actually forward biases the diode in the ckt &  $I_Q$  is the actual f.b. current.

- \*  $V_{DQ}$  &  $I_{DQ} \approx I_Q$  are the actual operating voltage & current in the ckt.
- \* Load line concept can be applied to any device in ckt to find the operating point.

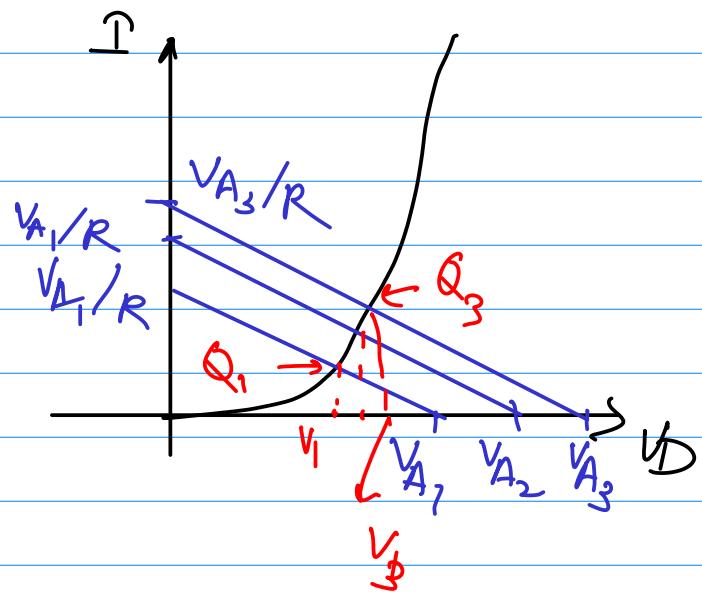


→ Load Line vs  $R$  &  $V_A$



$$R_1 > R_2 > R_3$$

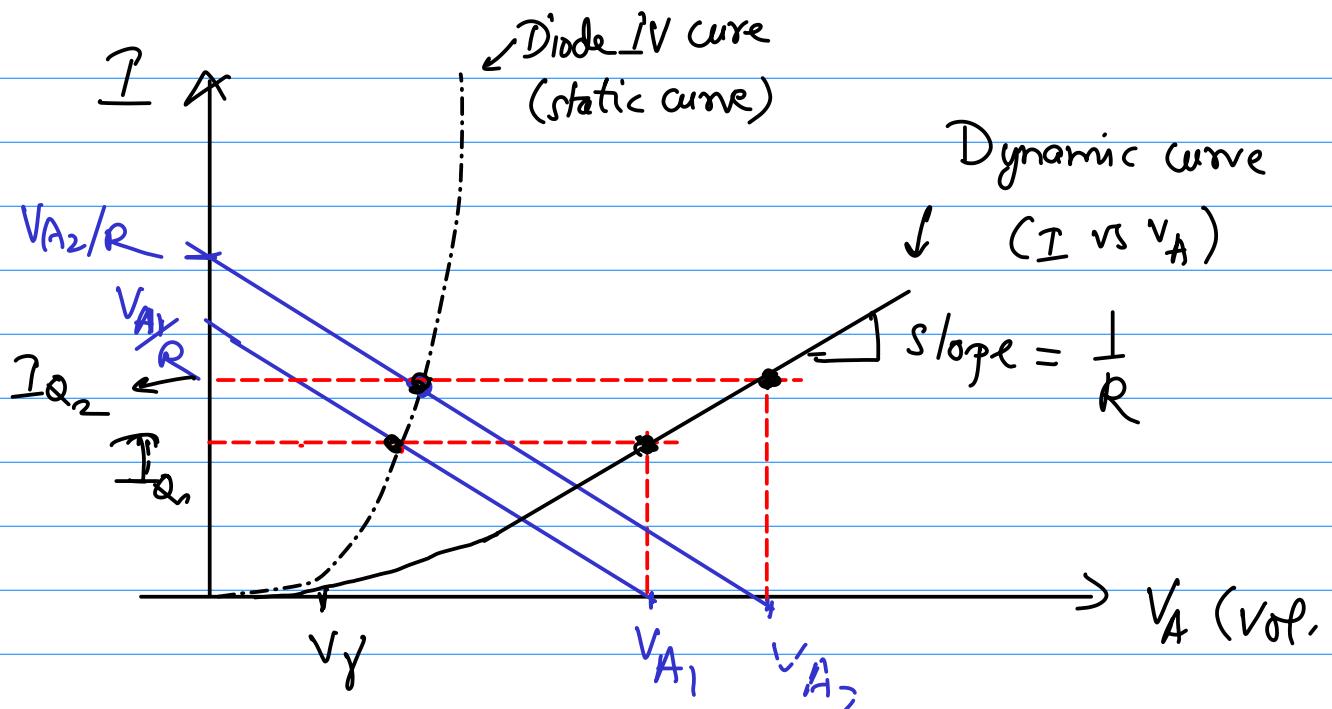
$$V_1 < V_2 < V_3$$



$$V_{A_1} < V_{A_2} < V_{A_3}$$

$$V_1 < V_2 < V_3$$

→ Dynamic ( $I$  -  $V$ ) curve - (ckt current  $I$  vs applied vol.  $V$ )



from load line KVL  $\rightarrow$

$$I = \frac{V_A - V_D}{R} \Rightarrow$$

$$\boxed{I = \frac{1}{R} V_A - \frac{1}{R} V_D}$$

—②

if  $I$  vs  $V_D$  is plotted from ②, then we get the load line (blue)

& if  $I$  vs  $V_A$  is plotted, we get the dynamic curve

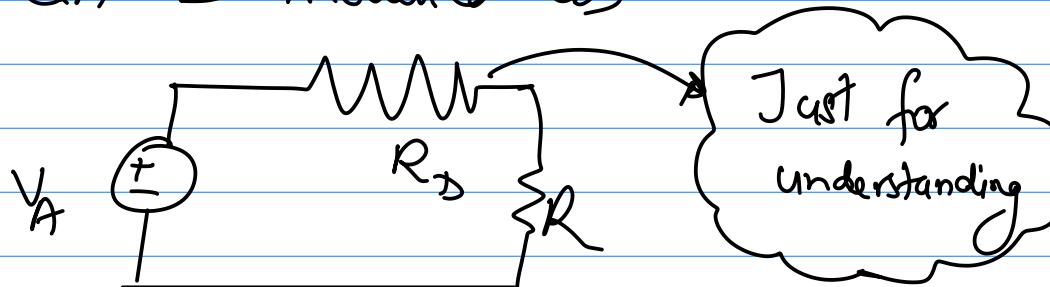
So, slope =  $+\frac{1}{R}$

\* At low  $V_A$ ,  $V_D$  will also be small. ( $V_A < V_Y$   
 $\therefore V_D < V_Y$ )

If  $V_D < V_Y$  then diode barrier is large.

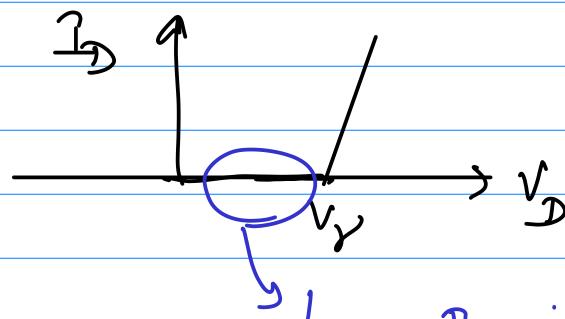
So, diode is less conductive or diode resist.  
 is large ( $R_D = \text{large}$ )

So, ckt can be modelled as



here  $R_D \gg R$

Remember



here  $I_D$  is v. small  
 or  $R_D$  is v. high

So, by KVL & potential division

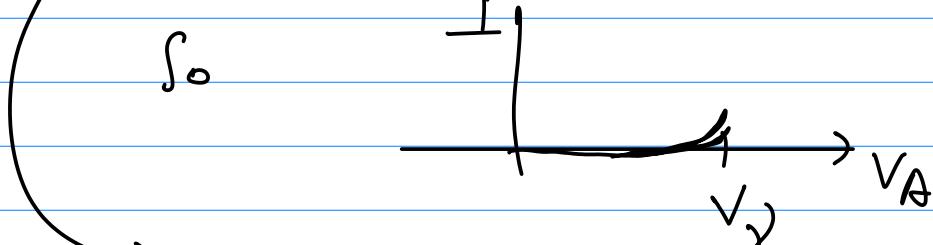
$$V_D = \left( \frac{R_D}{R_D + R} \right) V_A$$

$$\because R_D \gg R, \quad V_D \approx \frac{R_D}{R_D + R} V_A \rightarrow V_D \approx V_A$$

\* So if  $V_A < V_F$ , then  $V_D \approx V_A$  (Diode controls the current)

Since  $I$  vs  $V_D$  is exponential (diode IV)

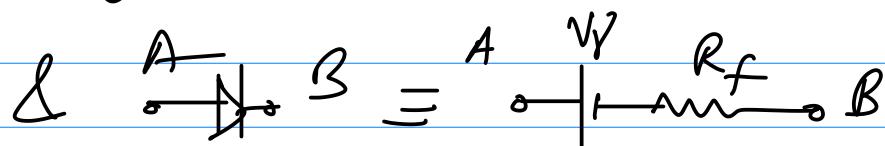
$I$  vs  $V_A$  also is exponential ( $\because V_D \approx V_A$ )



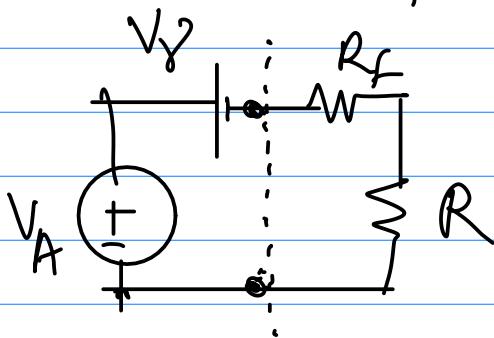
but this  $I$  is very small  $\because R_D$  large

\* As  $V_A \uparrow$  ( $V_A > V_F$ ), diode "turns-on".

barrier  $\rightarrow$  negligible,  $R_D \rightarrow R_f$  (small)



for  $V_A > V_F$



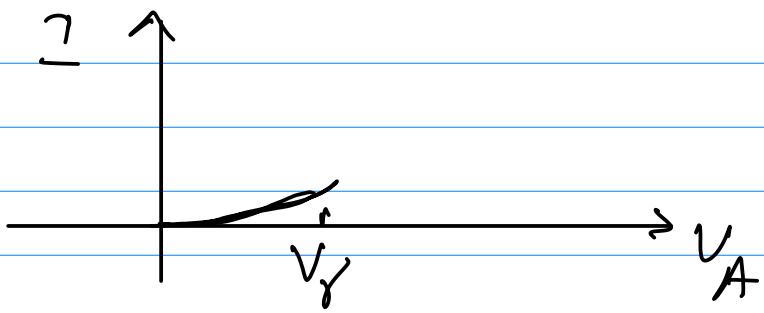
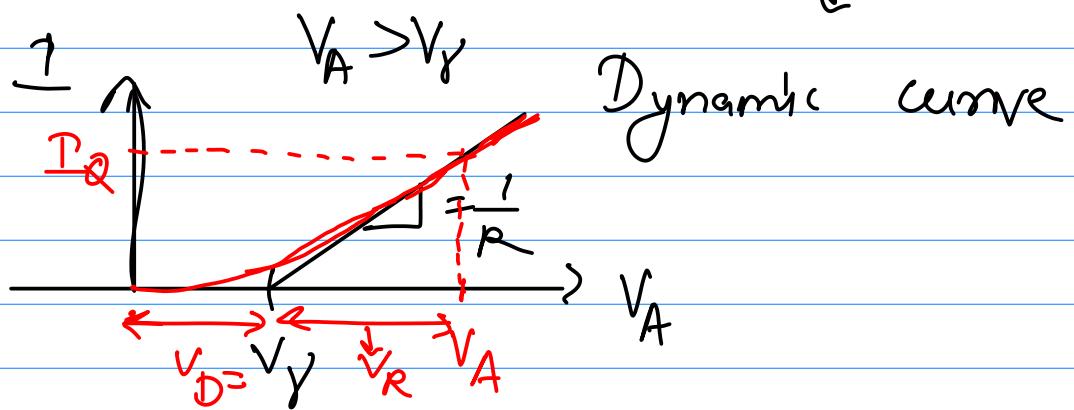
$$R_f \ll R$$

by KVL,

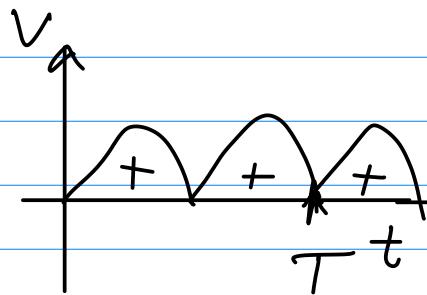
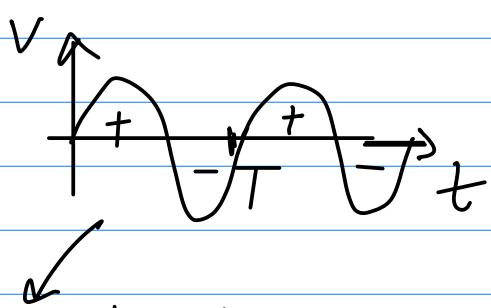
$$V_R = (V_A - V_F) \left( \frac{R}{R + R_f} \right)$$

as  $R \gg R_f$ ,  $\boxed{V_R = V_A - V_F} = IR$

$$\text{Now } I = \frac{V_A - V_Y}{R} \Rightarrow I = \frac{1}{R} V_A - \frac{V_Y}{R}$$



## → Rectifiers —



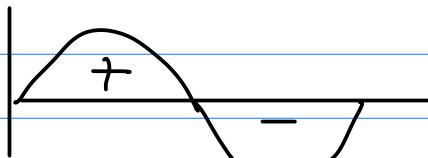
In ac signal

Avg. vol = 0

$$V_{avg} = \frac{1}{T} \int_0^T V(t) dt$$

Area under  
vol. curve

(+ve area + (-ve) area)

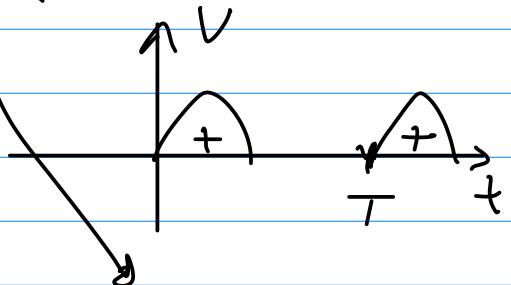


So, total area = 0

So,

$$\boxed{V_{avg} = 0}$$

(or)



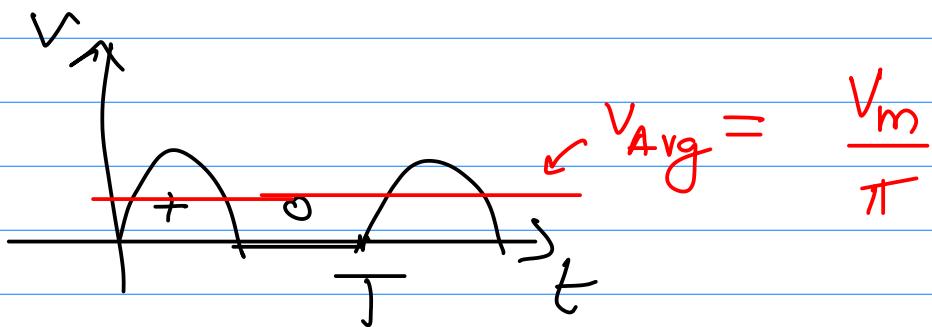
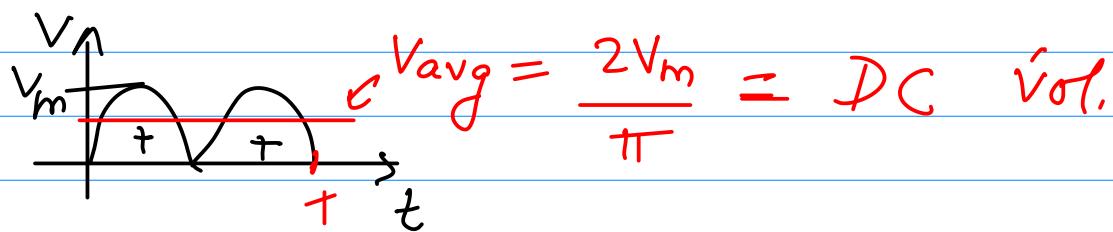
$V_{avg} = +ve$

$\therefore +ve \text{ area} \neq 0$

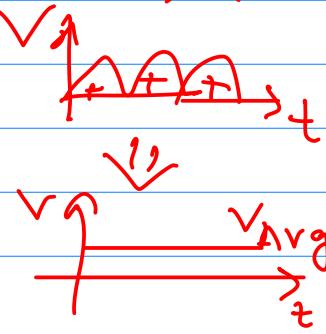
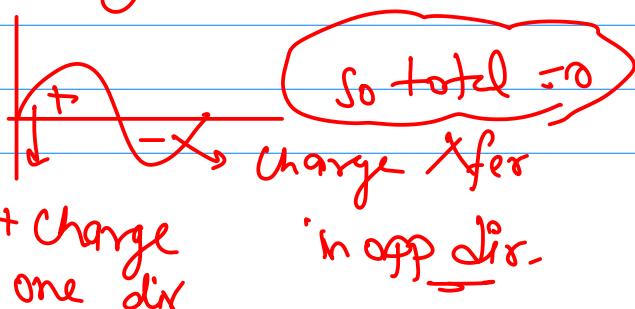
or +ve area  
+ (+ve) area

- \* So, Rectifier is used to get +ve avg vol. or current from a zero avg vol. or current signal (Symmetric ac)
- \* (Or) rectifier increases the avg vol. or current in a signal.

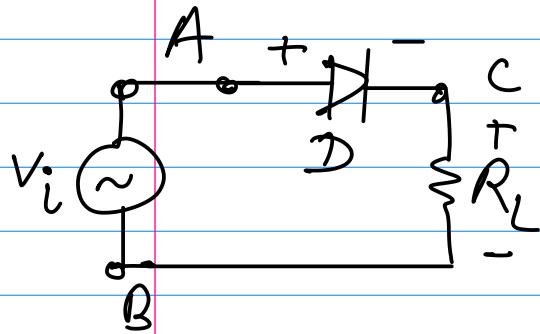
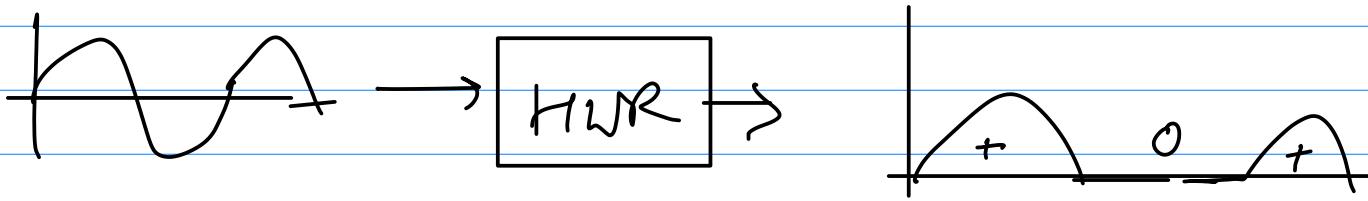
\* Avg vol can also be called 'dc' vol.



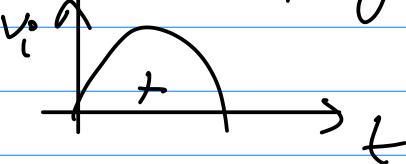
\* Avg vol is that Dc vol which if applied to a resistance will cause same amount of charge transfer as the original non constant signal



→ Half wave Rectifier (HWR) -



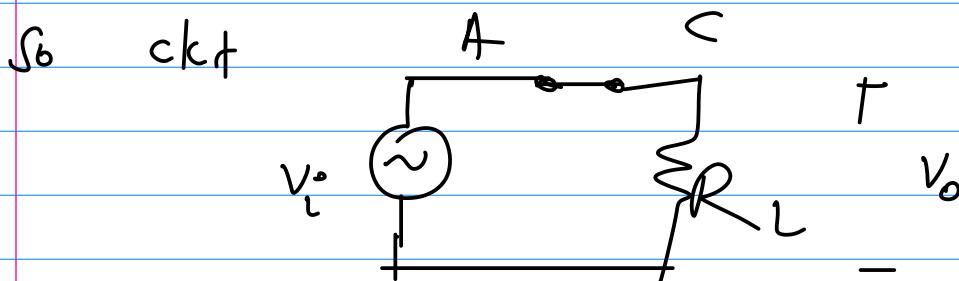
(i) for +ve half cycle of  $V_i$



$$V_A > V_B$$

$$V_A > V_C > V_B$$

So, Diode D is F.B.  $\overset{A}{\text{---}} \text{---} \overset{C}{\text{---}}$  =  $\overset{A}{\text{---}} \text{---} \overset{C}{\text{---}}$   
 (assuming ideal diode)



$$\text{By KVL, } V_i = V_o$$

